

Product Datasheet - Technical Specifications



More information in our Web-Shop at ▶ www.meilhaus.com

Your contact

Technical and commercial sales, price information, quotations, demo/test equipment, consulting:

Tel.: +49 - (0)81 41 - 52 71-0

E-Mail: sales@meilhaus.com

R&S®RTA4000 Oscilloscope Power of ten

1 200 MHz to 1 GHz 1 10-bit ADC

11 Gsample standard memory

3 year warranty



Data Sheet | Version 05.00

R&S®RTA4000 Oscilloscope At a glance

Designed with class-leading signal integrity and responsive ultra-deep memory, the R&S®RTA4000 brings the power of 10 to a new level.

A Rohde & Schwarz designed 10-bit ADC combined with class-leading low noise, memory depth and timebase accuracy gives you sharp waveforms, more accurate measurements and confidence when facing unexpected measurement challenges.

Rohde & Schwarz stands for quality, precision and innovation in all fields of wireless communications. As an independent, family-owned company, Rohde & Schwarz finances its growth from its own funds. The company plans for the long term to the benefit of its customers. Purchasing Rohde & Schwarz products is an investment for the future.

Traditionally, excellent signal integrity has been overlooked in the benchtop class of instruments because it is hard to accomplish and also expensive for instrument manufacturers. Users have had to compromise on measurement accuracy to get an affordable instrument that they could use for everyday debugging and troubleshooting tasks. With the R&S®RTA4000, signal integrity was at the forefront when we designed it.

The 10-bit A/D converter yields up to a fourfold improvement over conventional 8-bit A/D converters. The class-leading low noise allows users to take advantage of this extra vertical resolution. You get sharper waveforms with signal details that would have been hidden on other oscilloscopes in this class.

Oscilloscopes in the R&S®RTA4000 class have traditionally made users choose between deep memory and fast update rates. Each of these has its place, and having to choose one or the other means you may have the wrong tool for the problem you are addressing. The R&S®RTA4000 doesn't make you choose; it provides a fast update rate and ultra-deep memory to tackle any challenge that may come up.

The R&S®RTA4000 provides users with more than just an oscilloscope. It includes a logic analyzer, protocol analyzer, spectrum analyzer, waveform and pattern generator and digital voltmeter. A large, high-resolution capacitive touch-screen with a widely acclaimed user interface makes it easy to take advantage of all these tools.



Benefits

Unrivaled signal integrity

⊳ page 4

Capture more time at full bandwidth

⊳ page 5

Large high-resolution display in a compact form factor

⊳ page 6

Frequency response analysis (Bode plot)

⊳ page 8

Spectrum analysis: identify interactions between time and frequency

⊳ page 10

Protocol analysis: efficiently debug serial buses

⊳ page 11

The right probe for the best measurement

⊳ page 12

Capabilities to meet your needs today with insurance for the future

⊳ page 14

	R&S®RTC1000	R&S®RTB2000	R&S®RTM3000	R&S®RTA4000
Number of oscilloscope channels	2	2/4	2/4	4
Bandwidth in MHz	50, 70, 100, 200, 300	70, 100, 200, 300	100, 200, 350, 500, 1000	200, 350, 500, 1000
Max. sampling rate in Gsample/s	1/channel, 2 interleaved	1.25/channel, 2.5 interleaved	2.5/channel, 5 interleaved	2.5/channel, 5 interleaved
Max. memory depth in Msample	1/channel, 2 interleaved	10/channel, 20 interleaved; 160 Msample (optional) segmented memory	40/channel, 80 interleaved; 400 Msample (optional) segmented memory	100/channel, 200 interleaved; 1 Gsample (standard) segmented memory
Timebase accuracy in ppm	50	2.5	2.5	0.5
Vertical bits (ADC)	8	10	10	10
Min. input sensitivity	1 mV/div	1 mV/div	500 μV/div	500 μV/div
Display	6.5", 640 × 480 pixel	10" capacitive touch, 1280 × 800 pixel	10" capacitive touch, 1280 × 800 pixel	10" capacitive touch, 1280 × 800 pixel
Update rate	10 000 waveforms/s	300 000 waveforms/s in fast segmentated memory mode	2 000 000 waveforms/s in fast segmentated memory mode	2 000 000 waveforms/s in fast segmentated memory mode
MSO	8 channels, 1 Gsample/s	16 channels, 2.5 Gsample/s	16 channels, 5 Gsample/s	16 channels, 5 Gsample/s
Protocol (optional)	l ² C, SPI, UART/RS-232/ RS-422/RS-485, CAN, LIN	l ² C, SPI, UART/RS-232/ RS-422/RS-485, CAN, LIN	I ² C, SPI, UART/RS-232/RS-422/ RS-485, CAN, LIN, audio (I ² S/ LJ/RJ/TDM), ARINC, MIL	I ² C, SPI, UART/RS-232/ RS-422/RS-485, CAN, LIN, audio (I ² S), ARINC, MIL
Generator(s)	1 generator, 4-bit pattern generator	1 ARB, 4-bit pattern generator	1 ARB, 4-bit pattern generator	1 ARB, 4-bit pattern generator
Math	+,-,*,/,FFT(128k points)	+, -, *, /, FFT (128k points)	+,-,*,/,FFT (128k points), 21 advanced functions	+,-,*,/,FFT (128k points), 21 advanced functions
Rohde & Schwarz probe interface	-	-	standard	standard
RF capability	FFT	FFT	spectrum analysis 1)	spectrum analysis 1)

¹⁾ The R&S°RTM-K18 and R&S°RTA-K18 options are not distributed in North America.

Unrivaled signal integrity

10-bit ADC: 1024 levels, 4 times more than 8-bit ADC

0.6 % noise: at 1 mV/div, 200 MHz,

50 Ω ; % of full scale

500 μV/div: full bandwidth, no software magnification

10-bit ADC with up to 16-bit resolution

Rohde&Schwarz engineered a proprietary 10-bit A/D converter that delivers a fourfold improvement over conventional 8-bit A/D converters.

The increased resolution results in sharper waveforms with more signal details that would otherwise be missed. One example is the characterization of switched-mode power supplies. The voltages across the switching device must be determined during the on/off times within the same acquisition. For precise measurements of small voltage components, a high resolution of more than 8 bit is essential. With high resolution decimation, the R&S®RTA4000 even provides up to 16-bit vertical resolution, a resolution previously unseen in this class of instrument.

500 µV/div: full measurement bandwidth

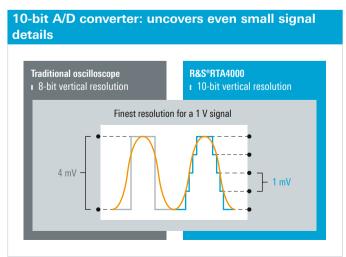
The R&S°RTA4000 oscilloscope offers outstanding sensitivity down to 500 $\mu\text{V/div}.$ Traditional oscilloscopes can only reach this level of input sensitivity by employing software-based magnification of larger settings or by limiting the bandwidth. The R&S°RTA4000 oscilloscope shows the signal's real sampling points over the full measurement bandwidth – even at 500 $\mu\text{V/div}.$

Class-leading low noise

Higher resolution is only beneficial if the extra bits are not consumed by the noise of the oscilloscope. The R&S®RTA4000 has class-leading low noise that allows you to take advantage of the extra bits of resolution and see signals that are hidden in the noise of other oscilloscopes.

The Rohde&Schwarz designed 10-bit A/D converter ensures highest signal fidelity at the highest resolution





Capture more time at full bandwidth

200 Msample: standard acquisition memory

1 Gsample: standard history and segmented mode

±0.5 ppm: timebase accuracy



Deep memory: standard 100 Msample per channel and 200 Msample interleaved

The R&S®RTA4000 offers class-leading memory depth: 100 Msample per channel, 200 Msample in interleaved mode. This is up to 10 times more than similar oscilloscopes in the same instrument class. Maintaining a fast sample rate is directly tied to acquisition memory. With its deep memory, the R&S®RTA4000 captures longer periods of time at high sample rates, giving you extra insurance for unexpected project requirements.

Class-leading timebase accuracy

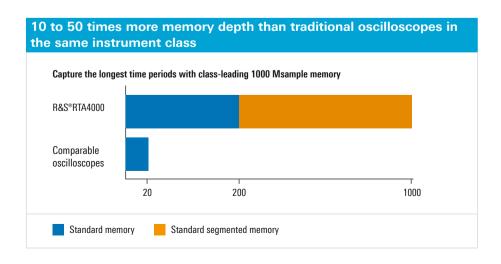
With a timebase accuracy of ± 0.5 ppm, the R&S®RTA4000 is 5 to 20 times better than other instruments in its class. An excellent timebase is important to ensure accurate measurements over long time captures.

Standard segmented memory: 1 Gsample

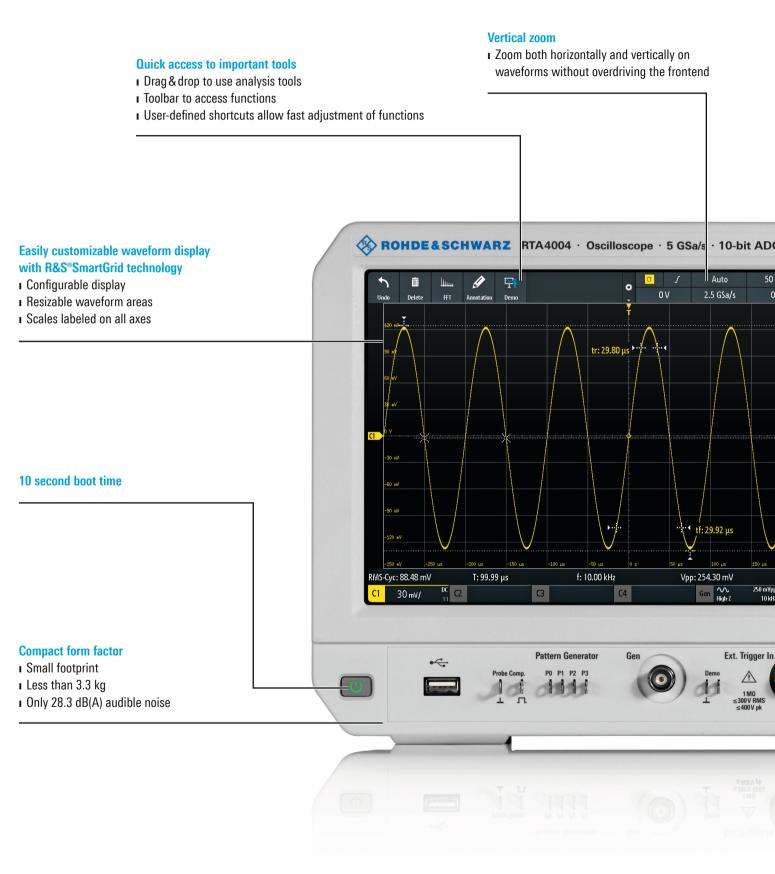
The standard segmented memory analyzes signal sequences over a long observation period. For example, protocol-based signals with communications gaps, such as I²C or SPI, can be captured over extended periods of time without wasting storage on idle time. Thanks to the variable segment size from 10 ksample to 200 Msample, the deep memory is optimally utilized; more than 87 000 cohesive individual segments are possible.

Standard history function

History mode is an always-on capability to view previous acquisitions up to the maximum segmented memory depth of 1 Gsample. For further analysis, the complete toolset can be applied to recorded segments. This includes, for example, mask tests, QuickMeas function and FFT.



Large high-resolution display in a compact for



m factor

10.1" high-resolution capacitive touchscreen with gesture support

- Gesture support for scaling and zooming
- High resolution: 1280 × 800 pixel
- 12 horizontal grid lines for more signal details

Documentation of results at the push of a button

Documentation as a screenshot or of instrument settings

Horizontal Sample West 12 .666 mV West 22 .666 mV West 22 .666 mV Ch 1 Ch 2 Ch 3 Scale



Integrated logic analyzer (MSO)

- 1 16 additional digital channels
- Synchronous and time-correlated analysis of analog and digital components of embedded designs
- User upgradeable

Color-coded controls indicate the selected channel

Standard history function

- Always-on capability to view previous acquisitions
- Over 1 Gsample
- More than 87 000 segments



Active probe interface

- Automatically detects and powers probes
- Rohde & Schwarz probes with probe interface
- More than 30 available probes

Frequency response analysis (Bode plot)

- I Analyze the frequency response of passive filters and amplifier circuits
- **I Perform control loop response measurements**
- I Perform power supply rejection ratio measurements
- **I** Simple and fast documentation

Perform low-frequency response analysis with an oscilloscope

The R&S®RTA-K36 frequency response analysis (Bode plot) option lets you perform low-frequency response analysis on your oscilloscope easily and quickly. It characterizes the frequency response of a variety of electronic devices, including passive filters and amplifier circuits. For switch mode power supplies, it measures the control loop response and power supply rejection ratio. The frequency response analysis option uses the oscilloscope's built-in waveform generator to create stimulus signals ranging from 10 Hz to 25 MHz. Measuring the ratio of the stimulus signal and the output signal of the DUT at each test frequency, the oscilloscope plots gain and phase logarithmically.



The R&S®RTA-K36 frequency response analysis (Bode plot) option characterizes the frequency response of a variety of electronic devices, including passive filters and amplifier circuits



The amplitude output level of the generator signal can be varied during the measurement to suppress the noise behavior of the DUT



The measurement resolution can be varied by changing the points per decade



A table of measurement results provides detailed information about each measurement point, consisting of frequency, gain and phase shift



Features and functionalities

Amplitude profile

The R&S®RTA-K36 frequency response analysis (Bode plot) option allows users to profile the amplitude output level of the generator. This helps to suppress the noise behavior of the DUT when performing a control loop response or power supply rejection ratio and to improve signal-to-noise ratio (SNR). It is possible to define up to 16 steps.

Improve resolution and markers support

You can choose the points per decade to set up and modify the resolution of your plot. The oscilloscope supports up to 500 points per decade. Markers can be dragged to the desired position, directly on the plotted trace. A legend displays the corresponding coordinates of the markers. To determine the crossover frequency, set one marker to 0 dB and the second marker to -180° phase shift. Now you can easily determine the phase and gain margin.

Measurement table

Furthermore, you can view the results in a table. The table of measurement results details information about each measured point, consisting of frequency, gain and phase shift. In case you use cursors, for ease of use, the associated row of the result table is highlighted. For reporting, screenshots, table results or both can be quickly saved to a USB device.

Broad probe portfolio

Accurate control loop response or power supply rejection ratio characterization highly depends on choosing the right probes, since peak-to-peak amplitudes of both V_{in} and V_{out} can be very low at some test frequencies. These values would be buried in the oscilloscope's noise floor and/or in the switching noise of the DUT itself. We recommend the low-noise R&S®RT-ZP1X 38 MHz bandwidth 1:1 passive probes. These reduce measurement noise and provide the best SNR.

Spectrum analysis: identify interactions between time and frequency

Spectrogram:

evolution over time

Peak markers:

automatic positioning



Fast and precise analysis

Difficult-to-find faults often result from the interaction between time and frequency signals. The R&S®RTA-K18¹¹ spectrum analysis and spectrogram option quickly finds such errors. Like on a spectrum analyzer, parameters such as center frequency and resolution bandwidth can be adapted to the specific measurement task. The oscilloscope automatically selects the relevant time domain settings. Optimum performance ensures the fastest multidomain analysis in this oscilloscope class.

1) The R&S®RTA-K18 option is not distributed in North America.

Parallel operation: correlation between frequency and time

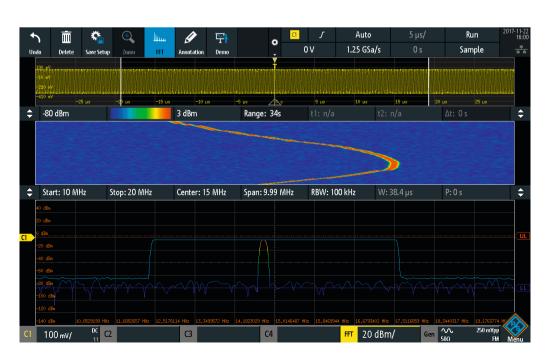
Advanced electronics is based on the seamless interaction between protocol-based interfaces, digital, analog and frequency components. Simultaneous analysis of all components is a must. Time, frequency and protocol information is correlated, and time references can be quickly recognized. Measurement windows help you select specific areas of the recording, which can simplify, for example, the acquisition of frequency switching operations.

Spectrogram: display of frequency over time

A spectrogram displays the spectrum of frequencies as they vary over time. For easy interpretation, the magnitude can be color-coded. Thanks to the high FFT rate, even fast frequency changes can be displayed. When used in combination with the history and segmented memory, the spectrogram marker shows the time of the acquisition and makes it possible to load the corresponding time and frequency waveforms onto the screen. All R&S®RTA4000 tools can be used to analyze the loaded waveforms.

Markers: find peaks automatically

Markers can be automatically positioned on the frequency peaks for fast analysis. An adaptable threshold defines the peaks. Parameters such as excursion and maximum peak width can be adjusted for in-depth analysis. Results can be compiled in a table (absolute or relative to a specific reference marker). Selectable delta measurements make it easy to adjust the distances between signal peaks.



Test signal from three different perspectives: time domain (top), spectrogram (center) and frequency domain (bottom)

Protocol analysis: efficiently debug serial buses



Protocol aware triggering and decoding for serial buses

Counting 1s and 0s to decode a serial bus is tedious and error-prone. The R&S®RTA4000 automates this process by decoding the waveforms into a specific protocol. In addition, protocol aware triggering directly triggers on specific parts of a packet or frame.

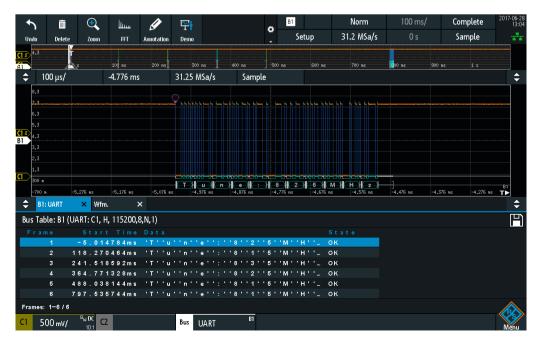
Segmented memory for long time captures

Standard segmented memory is ideal for serial protocols. It allows you to capture only relevant packets/frames and ignore the long idle time in between packets. With 1 Gsample of segmented memory available, you can capture more than 87 000 timestamped packets/frames.

Table view of packets/frames

A table view allows you to see a high-level representation of all captured packets. You can also export the table.

Supported buses	
Embedded	I PC I UART/RS-232/RS-422/RS-485 I SPI (2/3/4-wire)
Aerospace	I MIL-STD-1553 I ARINC 429
Automotive, industrial	ı CAN ı LIN
Audio	ı I ² S/LJ/RJ/TDM



Decoded hexadecimal I²C message shown in honeycomb format and in table

The right probe for the best measurement

More than 30: dedicated probes

Micro button: for convenient

instrument control

0.01% accuracy: with

R&S®ProbeMeter

Extensive probe range for all measurement tasks

A complete portfolio of high-quality passive and active probes covers all measurement tasks. With an input impedance of 1 M Ω , the active probes put only a minimum load on a signal source's operating point. The very large dynamic range, even at high frequencies, prevents signal distortion – for example: 60 V (V_{pp}) at 1 GHz for the active single-ended probes.

Complete portfolio for power measurements

The portfolio of dedicated probes for power measurements includes active and passive probes for the different voltage and current ranges – from μA to kA and from μV to kV. Dedicated power rail probes detect even small and sporadic distortions on DC power rails.

Micro button for convenient instrument control

The situation is all too familiar. You've carefully positioned the probe on the device under test and want to start the measurements – but you don't have a free hand. The micro button on Rohde & Schwarz active probes solves this problem. It is conveniently situated on the probe tip, and you

can assign it different functions, such as run/stop, autoset and adjust offset.

R&S®ProbeMeter: integrated voltmeter for precise DC measurements

One connection lets you see the oscilloscope waveform and gives you access to a highly accurate voltmeter that shows the DC value regardless of other instrument settings.

▶ For more information, see the product brochure: Probes and accessories for Rohde & Schwarz oscilloscopes (PD 3606.8866.12).



Practical design: micro button for convenient instrument control; diverse probe tips and ground cables are included as standard accessories

Probe type	Ideal for measuring	Recommended probes
Standard passive probe	Single-ended voltages, max. bandwidth 500 MHz	R&S®RT-ZP10 comes as standard with the R&S®RTA4000
Active broadband probe	Singled-ended voltages, up to 8 GHz bandwidth	R&S®RT-ZS10E, R&S®RT-ZS10, R&S®RT-ZS20
Power integrity probe	Disturbances on power rails with high offsets, greater than 2 GHz bandwidth	R&S®RT-ZPR20
High voltage probe	High single-ended and differential voltages, up to 6 kV	R&S°RT-ZHD007, R&S°RT-ZHD15, R&S°RT-ZHD16, R&S°RT-ZHD60
Current probe	Currents from µAs to kAs	R&S°RT-ZC05B, R&S°RT-ZC10B, R&S°RT-ZC15B, R&S°RT-ZC20B, R&S°RT-ZC30
EMC near-field probe	EMI debugging up to 3 GHz	R&S®HZ-15

Common applications



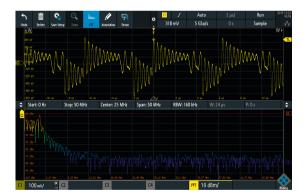
Power integrity

- Measure large DC offsets with the ability to zoom in on small ripples
- Accurately measure ripple and periodic and random disturbances
- I Spectrum analysis view makes finding coupled sources easier



Power analysis

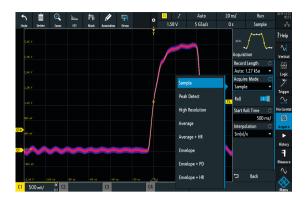
- I See power signal details with up to 16-bit resolution
- I Capture long periods of time, e.g. a turn-on sequence, with high sample rate
- Complete probe portfolio for measuring from μA to kA and μV to kV



EMI debugging

- Near-field probes allow you to sniff out interfering signals
- I Time and frequency domain correlation for powerful debugging of
- I FFT provides a vivid and fast view in the frequency domain

Capabilities to meet your needs today with ins



Acquisition modes

- High-resolution: up to 16-bit vertical resolution
- Averaging: up to 100000 waveforms
- Peak detect
- Envelope
- Averaging plus high resolution
- I Envelope plus peak detect
- Envelope plus high resolution



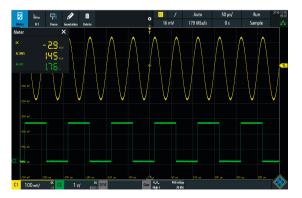
Math and measurements

- I Up to five basic or advanced math waveforms
- Advanced math includes equation editor with 30 options
- I Up to eight measurements at once
- Over 40 automated measurement options available for each measurement
- I Gated measurements and statistics



Annotation, R&S®SmartGrid and documentation

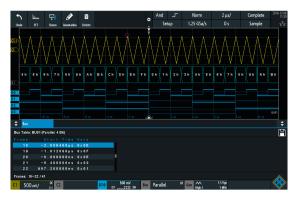
- I Simplified documentation at the push of a button
- I On-screen annotation using the touch display for specific notes
- R&S®SmartGrid to easily resize/layout/configure the display as needed
- Graticule annotation makes it easy to quickly see the V/div and timebase setting



Digital voltmeter

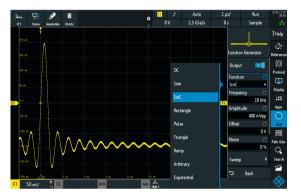
- Integrated 3-digit voltmeter (DVM)
- Integrated 6-digit frequency counter
- I Always on, even when the oscilloscope is stopped
- Measurement functions include DC, AC + DC (RMS) and AC (RMS)

urance for the future



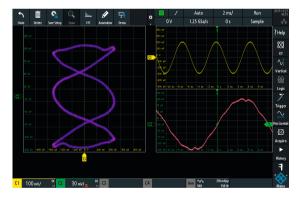
Mixed signal

- Integrated digital channels (16 channels) allow correlated measurements between analog and digital signals
- I Up to 5 Gsample/s sample rate for high timing resolution
- I Up to 200 Msample of memory allows long time captures
- I Ideal for low-speed serial bus analysis



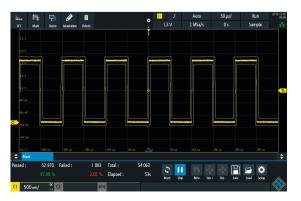
Waveform and pattern generator

- Integrated arbitrary waveform generator to produce signals for device stimulus
- High sample rate (250 Msample/s) and resolution (14 bit) allows accurate signal reproduction
- Modulation and swept mode capabilities
- $_{\text{I}}$ 50 Ω (2.5 V (V $_{_{DD}}))$ and 1 M Ω (10 V (V $_{_{DD}}))$ output
- 4-bit pattern generator with predefined patterns and the ability to import user-defined patterns



XY mode

- I Plot the voltage levels of two channels against each other
- Measure phase shift



Mask test mode

- Fast limit testing to see if a waveform violates a configured set of conditions
- Import user-defined masks or create a mask of a known good waveform on the oscilloscope
- I Save screenshots, waveforms; output a beep or pulse on violations

And there is so much more ...

- ı Efficient reporting capabilities
- ı Localized GUI and online help
- ı Fully upgradeable via software licenses
- I Web server functionality for instrument access
- I Extensive range of probes and accessories



Grows with your needs

The R&S®RTA4000 oscilloscopes flexibly adapt to needed project updates. You simply install the necessary software licenses, e.g. triggering and decoding of serial protocols. The waveform and pattern generator and MSO capabilities ¹⁾ are built-in and just need to be activated. The bandwidth can be upgraded up to 1 GHz via keycode. All this makes retrofitting really easy.

Multilingual support: choose among thirteen languages

The R&S®RTA4000 oscilloscope's user interface and online help support thirteen languages (English, German, French, Spanish, Italian, Portuguese, Czech, Polish, Russian, simplified and traditional Chinese, Korean and Japanese). You can change the language in just a few seconds while the instrument is running.

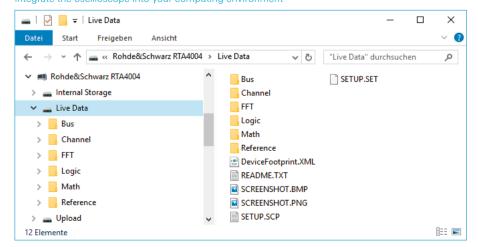
Protection of data

The secure erase function protects sensitive data. This function removes all user data and settings, including device setups and reference waveforms.

Connectivity

The R&S®RTA4000 can be directly connected to a PC via the built-in USB host and USB device ports. The USB host transfers screenshots and instrument settings to a USB stick. Media transfer protocol (MTP) implementation ensures seamless integration. The USB device port and the LAN interface enable remote control. The built-in web server functionality allows you to control the oscilloscope and display your screen content to an audience. Data and programming interfaces are included, e.g. for seamless MATLAB® integration.

With the USB MTP implementation, you can easily access live channel data and screenshots and integrate the oscilloscope into your computing environment



The R&S®RTA-B1 MSO option additionally contains two logic probes with 16 digital channels.

Specifications in brief

Specifications in brief		
Vertical system		
Number of channels	R&S®RTA4004	4
Bandwidth (-3 dB)	R&S®RTA4004 (with R&S®RTA-B24x options)	200 MHz, 350 MHz, 500 MHz, 1 GHz
Rise time (calculated)	R&S®RTA4004 (with R&S®RTA-B24x options)	5 ns, 3.5 ns, 1.75 ns, 1.15 ns
Input sensitivity	max. bandwidth in all ranges	
	at 1 MΩ	500 μV/div to 10 V/div
	at 50 Ω	500 μV/div to 1 V/div
DC gain accuracy	offset and position = 0, maximum operating to	emperature change of ±5°C after self-alignment
	input sensitivity > 5 mV/div	±1% of full scale
	input sensitivity ≤ 5 mV/div to ≥ 1 mV/div	±1.5% of full scale
	input sensitivity < 1 mV/div	±2.5% of full scale
ADC resolution		10 bit, up to 16 bit with high resolution decimation
Acquisition system		
Maximum realtime sampling rate		2.5 Gsample/s; 5 Gsample/s, interleaved
Acquisition memory		100 Msample (200 Msample, interleaved); 1 Gsample segmented memory
Horizontal system		
Timebase range		selectable between 0.5 ns/div and 500 s/div
Trigger system		
Trigger types	standard	edge, width, video (PAL, NTSC, SECAM, PAL-M, SDTV 576i, HDTV 720p, HDTV 1080i, HDTV 1080p), pattern, line, serial bus
	option	I ² C, SPI, UART/RS-232/RS-422/RS-485, CAN/LIN, audio (I ² S), ARINC 429, MIL-STD-1553
MSO option		
Digital channels		16 (2 logic probes)
Sampling rate		2.5 Gsample/s; 5 Gsample/s, interleaved
Acquisition memory		10 Msample
Waveform generator		
Resolution, sample rate		14 bit, 250 Msample/s
Amplitude	high Z; 50 Ω	20 mV to 10 V (V _{pp}); 10 mV to 5 V (V _{pp})
DC offset	high Z; 50 Ω	±5 V; ±2.5 V
General data		
Screen		10.1" WXGA TFT color display (1280 × 800 pixel)
Interfaces		USB host with MTP, USB device, LAN, powerful web server for remote display and operation
Audible noise	maximum sound pressure level at a distance of 1.0 m	28.3 dB(A)
Dimensions	$W \times H \times D$	390 mm × 220 mm × 152 mm (15.4 in × 8.66 in × 5.98 in)
Weight		3.3 kg (7.3 lb)

RMS noise flo	RMS noise floor at 50 Ω (meas.)				
Input sensitivity	R&S®RTA4004	R&S®RTA4004 + R&S®RTA-B243	R&S®RTA4004 + R&S®RTA-B245	R&S®RTA4004 + R&S®RTA-B2410	
■ 1 V/div	₁ 22.7 mV	ı 22.8 mV	1 25.1 mV	■ 31.4 mV	
■ 500 mV/div	■ 12.6 mV	■ 13.7 mV	■ 15.4 mV	₁ 19.8 mV	
■ 200 mV/div	■ 5.5 mV	₁ 6.2 mV	₁ 7.0 mV	■ 9.1 mV	
■ 100 mV/div	■ 2.7 mV	1 3.0 mV	■ 3.4 mV	1 4.6 mV	
■ 50 mV/div	₁ 1.4 mV	1.6 mV	1.8 mV	■ 2.4 mV	
■ 20 mV/div	■ 0.53 mV	■ 0.58 mV	■ 0.65 mV	■ 0.86 mV	
■ 10 mV/div	■ 0.26 mV	■ 0.28 mV	■ 0.32 mV	■ 0.41 mV	
■ 5 mV/div	■ 0.15 mV	■ 0.18 mV	■ 0.20 mV	■ 0.27 mV	
■ 2 mV/div	■ 0.07 mV	■ 0.09 mV	■ 0.10 mV	■ 0.13 mV	
■ 1 mV/div	■ 0.06 mV	■ 0.07 mV	■ 0.08 mV	■ 0.11 mV	
■ 0.5 mV/div	ı 0.05 mV	I 0.07 mV	■ 0.08 mV	■ 0.11 mV	

Oscilloscope portfolio









		10 000		
R&S®	RTH1000	RTC1000	RTB2000	RTM3000
Vertical				
Bandwidth	60/100/200/350/500 MHz ¹⁾	50/70/100/200/300 MHz ¹⁾	70/100/200/300 MHz ¹⁾	100/200/350/500 MHz/1 GHz ¹⁾
Number of channels	2 plus DMM/4	2	2/4	2/4
Resolution	10 bit	8 bit	10 bit	10 bit
V/div 1 MΩ	2 mV to 100 V	1 mV to 10 V	1 mV to 5 V	500 μV to 10 V
V/div 50 Ω	-			500 μV to 1 V
Horizontal				
Sampling rate per channel (in Gsample/s)	1.25 (4-channel model); 2.5 (2-channel model); 5 (all channels interleaved)	1; 2 (2 channels interleaved)	1.25; 2.5 (2 channels interleaved)	2.5; 5 (2 channels interleaved)
Max. memory (per channel/1 channel active)	125 ksample (4-channel model); 250 ksample (2-channel model); 500 ksample (50 Msample in segmented memory mode ²)	1 Msample; 2 Msample	10 Msample; 20 Msample (160 Msample in segmented memory mode ²⁾)	40 Msample; 80 Msample (400 Msample in segmented memory mode ²)
Segmented memory	option	_	option	option
Acquisition rate (in waveforms/s)	50 000	10 000	50 000 (300 000 in fast segmented memory mode ²⁾)	64000 (2000000 in fast segmented memory mode ²)
Trigger			mented memory mode 7	memory mode γ
Options	advanced, digital trigger	elementary (5 trigger types)	basic (7 trigger types)	basic (10 trigger types)
Орнопа	(14 trigger types) ²⁾	cicinentary (5 trigger types)	basic (7 trigger types)	basic (10 trigger types)
Mixed signal option				
No. of digital channels 1)	8	8	16	16
Sampling rate of digital channels (in Gsample/s)	1.25	1	1.25	two logic probes: 2.5 on each channel; one logic probe: 5 on each channel
Memory of digital channels	125 ksample	1 Msample	10 Msample	two logic probes: 40 Msample per channel; one logic probe: 80 Msample per channel
Analysis				
Cursor meas. types	4	13	4	4
Stand. meas. functions	33	31	32	32
Mask test	elementary (tolerance mask	elementary (tolerance mask	elementary (tolerance mask	elementary (tolerance mask around
	around the signal)	around the signal)	around the signal)	the signal)
Mathematics	elementary	elementary	basic (math on math)	basic (math on math)
Serial protocols triggering and decoding ¹⁾	I ² C, SPI, UART/RS-232/RS-422/ RS-485, CAN, LIN, CAN-FD, SENT (7)	I ² C, SPI, UART/RS-232/ RS-422/RS-485, CAN, LIN (5)	I ² C, SPI, UART/RS-232/RS-422/ RS-485, CAN, LIN (5)	I ² C, SPI, UART/RS-232/ RS-422/RS-485, CAN, LIN, I ² S, MIL-STD-1553, ARINC 429 (8)
Display functions	data logger	-	-	-
Applications 1), 2)	high-resolution frequency counter,	digital voltmeter (DVM), com-	digital voltmeter (DVM),	power, digital voltmeter (DVM), spectrum analysis
	advanced spectrum analysis, harmonics analysis	ponent tester, fast Fourier transform (FFT)	fast Fourier transform (FFT), frequency response analysis 3)	and spectrogram, frequency response analysis 3)
Compliance testing 1), 2)	advanced spectrum analysis,	ponent tester, fast Fourier		and spectrogram, frequency response analysis 3)
Compliance testing 1), 2) Display and operation	advanced spectrum analysis, harmonics analysis	ponent tester, fast Fourier transform (FFT)	frequency response analysis 3)	
	advanced spectrum analysis, harmonics analysis	ponent tester, fast Fourier transform (FFT)	frequency response analysis 3)	
Display and operation	advanced spectrum analysis, harmonics analysis	ponent tester, fast Fourier transform (FFT)	frequency response analysis ³⁾	10.1", color, 1280 × 800 pixel
Display and operation Size and resolution	advanced spectrum analysis, harmonics analysis - 7", color, 800 × 480 pixel optimized for touchscreen operation, parallel button	ponent tester, fast Fourier transform (FFT) - 6.5", color, 640 × 480 pixel optimized for fast button	frequency response analysis 3) - 10.1", color, 1280 × 800 pixel	10.1", color, 1280 × 800 pixel
Display and operation Size and resolution Operation	advanced spectrum analysis, harmonics analysis - 7", color, 800 × 480 pixel optimized for touchscreen operation, parallel button	ponent tester, fast Fourier transform (FFT) - 6.5", color, 640 × 480 pixel optimized for fast button	frequency response analysis 3) - 10.1", color, 1280 × 800 pixel	10.1", color, 1280 × 800 pixel
Display and operation Size and resolution Operation General data Dimensions in mm	advanced spectrum analysis, harmonics analysis - 7", color, 800 × 480 pixel optimized for touchscreen operation, parallel button operation	ponent tester, fast Fourier transform (FFT) 6.5", color, 640 × 480 pixel optimized for fast button operation	frequency response analysis ³⁾ - 10.1", color, 1280 × 800 pixel optimized for touchscreen opera	10.1", color, 1280 × 800 pixel tion, parallel button operation

¹⁾ Upgradeable.

²⁾ Requires an option.

³⁾ Available Q1 2019.

	HD	HD	HD 16 bit
Multi	Multi	Multi	Multi
	@ ± 622		
RTA4000	RTE1000	RTO2000	RTP
	200/350/500 MHz/1/1.5/2 GHz ¹⁾	600 MHz/1/2/3/4/6 GHz ¹⁾	4/6/8/13/16 GHz ¹⁾
4	2/4	2/4 (only 4 channels in 4 GHz and 6 GHz models)	4
10 bit	8 bit (up to 16 bit with HD mode)	8 bit (up to 16 bit with HD mode) ²⁾	8 bit (up to 16 bit with HD mode) ²⁾
500 μV to 10 V	$500~\mu V$ to $10~V$	1 mV to 10 V (500 μ V to 10 V) $^{2)}$	
500 μV to 1 V	$500~\mu V$ to $1~V$	1 mV to 1 V (500 μV to 1 V) ²⁾	1 mV to 1 V
2.5; 5 (2 channels interleaved)	5	10; 20 (2 channels interleaved in 4 GHz and 6 GHz model)	20
100 Msample; 200 Msample (1 Gsample in segmented memory mode)	50 Msample/200 Msample	standard: 50 Msample/200 Msample; max. upgrade: 1 Gsample/2 Gsample	standard: 50 Msample/200 Msample; max. upgrade: 1 Gsample/2 Gsample
standard	standard	standard	standard
64000 (2000000 in fast segmented	1 000 000 (1 600 000 in ultra-segmented	1000000 (2500000 in ultra-segmented memory mode)	950 000 (3 200 000 in ultra-segmented memory mode)
memory mode)	memory mode)	mode)	mode)
basic (10 trigger types)	advanced, digital trigger (13 trigger types)	advanced (includes zone trigger), digital trigger (14 trigger types) ²⁾	advanced, digital trigger (14 trigger types) with realtime deembedding ²⁾ , zone trigger ²⁾
		(1.1.1.990.1700)	realismo acomposating 7 zone angger
16	16	16	16
two logic probes: 2.5 on each channel; one logic probe: 5 on each channel	5	5	5
two logic probes: 100 Msample per channel; one logic probe: 200 Msample per channel	100 Msample	200 Msample	200 Msample
4	3	3	3
32	47	47	47
	advanced (user-configurable, hardware based)	advanced (user-configurable, hardware based)	advanced (user-configurable, hardware based)
basic (math on math)	advanced (formula editor)	advanced (formula editor)	advanced (formula editor)
RS-485, CAN, LIN, I ² S, MIL-STD-1553, ARINC 429 (8)	I ² C, SPI, UART/RS-232/RS-422/RS-485, CAN, LIN, I ² S, MIL-STD-1553, ARINC 429, FlexRay™, CAN-FD, USB 2.0/HSIC, Ethernet, Manchester, NRZ, SENT, SpaceWire, CXPI, USB Power Delivery, automotive Ethernet 100BASE-T1 (19)	I²C, SPI, UART/RS-232/RS-422/RS-485, CAN, LIN, I²S, MIL-STD-1553, ARINC 429, FlexRay™, CAN-FD, MIPI RFFE, USB 2.0/HSIC, MDIO, 8b10b, Ethernet, Manchester, NRZ, SENT, MIPI D-PHY, SpaceWire, MIPI M-PHY/UniPro, CXPI, USB 3.1 Gen1, USB-SSIC, PCle 1.1/2.0, USB Power Delivery, automotive Ethernet 100BASE-T1 (27)	I ² C, SPI, UART/RS-232/RS-422/RS-485, CAN, LIN, CAN-FD, MIPI RFFE, USB 2.0/ HSIC, MDIO 8b10b, Ethernet, Manchester, NRZ, MIPI D-PHY MIPI M-PHY/UniPro, USB 3.1 Gen1, USB-SSIC, PCIe 1.1/2.0, USB Power Delivery, automotive Ethernet 100BASE-T1 (20)
-	histogram, trend, track ²⁾	histogram, trend, track ²⁾	histogram, trend, track
	power, 16-bit high definition mode (standard), advanced spectrum analysis and	power, 16-bit high definition mode, advanced spectrum analysis and spectrogram, jitter, clock	16-bit high definition mode, advanced spectrum analysis and spectrogram, jitter, RF analysis,
spectrum analysis and spectrogram,	•		
spectrum analysis and spectrogram, frequency response analysis 3)	spectrogram	data recovery, I/Q data, RF analysis	realtime deembedding
spectrum analysis and spectrogram, frequency response analysis 3)	•	data recovery, I/Q data, RF analysis various options available (see PD 3607.2684.22)	various options available (see PD 5215.4152.22)
spectrum analysis and spectrogram, frequency response analysis 3)	spectrogram		-

427 × 249 × 204

9.6

390 × 220 × 152

3.3

427 × 249 × 204

8.6

441 × 285 × 316

18

Base unit

Vertical system

Input channels	R&S®RTA4004	4 channels
Input impedance		50 Ω ± 1.5 % (meas.)
		1 MΩ ± 1 % 14 pF ± 1 pF (meas.)
Analog bandwidth (–3 dB)	at 50 Ω input impedance	
	R&S®RTA4004	> 200 MHz
	R&S®RTA4004 with -B243 option	> 350 MHz
	R&S®RTA4004 with -B245 option	> 500 MHz
	R&S®RTA4004 with -B2410 option	> 1 GHz
	at 1 MΩ input impedance	
	R&S®RTA4004 with	> 200 MHz (meas.)
	R&S®RTA4004 with -B243 option	> 350 MHz (meas.)
	R&S®RTA4004 with -B245 option	> 500 MHz (meas.)
	R&S®RTA4004 with -B2410 option	> 500 MHz (meas.)
Lower frequency limit (–3 dB)	at AC coupling	< 5 Hz (meas.)
Analog bandwidth limits	at 50 Ω input impedance	()
analog banaman mine	R&S®RTA4004	20 MHz, 100 MHz
	R&S®RTA4004 with -B243 option	20 MHz, 100 MHz, 200 MHz
	R&S®RTA4004 with -B245 option	20 MHz, 100 MHz, 200 MHz, 350 MHz
	R&S®RTA4004 with -B2410 option	20 MHz, 100 MHz, 200 MHz, 350 MHz,
	100 1174004 Willi -D2410 Option	500 MHz
	at 1 MO input impadance	300 MHZ
	at 1 MΩ input impedance	20 MHz 100 MHz
	R&S®RTA4004	20 MHz, 100 MHz
	R&S®RTA4004 with -B243 option	20 MHz, 100 MHz, 200 MHz
	R&S®RTA4004 with -B245 option and	20 MHz, 100 MHz, 200 MHz, 350 MHz
	R&S®RTA4004 with -B2410 option	
Rise time (calculated)	R&S®RTA4004	< 1.75 ns
	R&S®RTA4004 with -B243 option	< 1 ns
	R&S®RTA4004 with -B245 option	< 700 ps
	R&S®RTA4004 with -B2410 option	< 350 ps
Vertical resolution		10 bit, up to 16 bit with high resolution
		decimation
DC gain accuracy	offset and position = 0	
,	maximum operating temperature change of	f ±5 °C after self-alignment
	input sensitivity > 5 mV/div	±1 %
		_ · /·
		+1 5 %
	input sensitivity	±1.5 %
	input sensitivity ≤ 5 mV/div to ≥ 1 mV/div	
Input coupling	input sensitivity	±2.5 %
Input coupling	input sensitivity ≤ 5 mV/div to ≥ 1 mV/div input sensitivity < 1 mV/div	±2.5 % DC, AC, GND
Input coupling Input sensitivity	input sensitivity ≤ 5 mV/div to ≥ 1 mV/div input sensitivity < 1 mV/div at 50 Ω	±2.5 % DC, AC, GND 0.5 mV/div to 1 V/div
Input sensitivity	input sensitivity $\leq 5 \text{ mV/div to} \geq 1 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ at 50Ω at $1 \text{ M}\Omega$	±2.5 % DC, AC, GND 0.5 mV/div to 1 V/div 0.5 mV/div to 10 V/div
	input sensitivity $\leq 5 \text{ mV/div to} \geq 1 \text{ mV/div}$ input sensitivity < 1 mV/div $\text{at } 50 \ \Omega$ at 1 M Ω at 50 Ω	±2.5 % DC, AC, GND 0.5 mV/div to 1 V/div 0.5 mV/div to 10 V/div 5 V (RMS), max. 30 V (V _p)
Input sensitivity	input sensitivity $\leq 5 \text{ mV/div to} \geq 1 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ at 50Ω at $1 \text{ M}\Omega$	±2.5 % DC, AC, GND 0.5 mV/div to 1 V/div 0.5 mV/div to 10 V/div 5 V (RMS), max. 30 V (V _p) 300 V (RMS), 400 V (V _p), derates at
Input sensitivity	input sensitivity $\leq 5 \text{ mV/div to} \geq 1 \text{ mV/div}$ input sensitivity < 1 mV/div $\text{at } 50 \ \Omega$ at 1 M Ω at 50 Ω	±2.5 % DC, AC, GND 0.5 mV/div to 1 V/div 0.5 mV/div to 10 V/div 5 V (RMS), max. 30 V (V _p) 300 V (RMS), 400 V (V _p), derates at 20 dB/decade to 5 V (RMS) above
Input sensitivity Maximum input voltage	input sensitivity $\leq 5 \text{ mV/div to} \geq 1 \text{ mV/div}$ input sensitivity < 1 mV/div $\text{at } 50 \ \Omega$ at 1 M Ω at 50 Ω	±2.5 % DC, AC, GND 0.5 mV/div to 1 V/div 0.5 mV/div to 10 V/div 5 V (RMS), max. 30 V (V _p) 300 V (RMS), 400 V (V _p), derates at 20 dB/decade to 5 V (RMS) above 250 kHz
Input sensitivity Maximum input voltage Position range	input sensitivity $\leq 5 \text{ mV/div to} \geq 1 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ at 50Ω at $1 \text{ M}\Omega$ at 50Ω at $1 \text{ M}\Omega$	±2.5 % DC, AC, GND 0.5 mV/div to 1 V/div 0.5 mV/div to 10 V/div 5 V (RMS), max. 30 V (V _p) 300 V (RMS), 400 V (V _p), derates at 20 dB/decade to 5 V (RMS) above
Input sensitivity Maximum input voltage Position range	input sensitivity $\leq 5 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ at 50Ω at $1 M\Omega$ at 50Ω at $1 M\Omega$	±2.5 % DC, AC, GND 0.5 mV/div to 1 V/div 0.5 mV/div to 10 V/div 5 V (RMS), max. 30 V (V _p) 300 V (RMS), 400 V (V _p), derates at 20 dB/decade to 5 V (RMS) above 250 kHz
Input sensitivity	input sensitivity $\leq 5 \text{ mV/div to} \geq 1 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ at 50Ω at $1 \text{ M}\Omega$ at 50Ω at $1 \text{ M}\Omega$	±2.5 % DC, AC, GND 0.5 mV/div to 1 V/div 0.5 mV/div to 10 V/div 5 V (RMS), max. 30 V (V _p) 300 V (RMS), 400 V (V _p), derates at 20 dB/decade to 5 V (RMS) above 250 kHz ±5 div ±(30 V – 5 div × input sensitivity)
Input sensitivity Maximum input voltage Position range	input sensitivity $\leq 5 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ at 50Ω at $1 M\Omega$ at 50Ω at $1 M\Omega$	±2.5 % DC, AC, GND 0.5 mV/div to 1 V/div 0.5 mV/div to 10 V/div 5 V (RMS), max. 30 V (V _p) 300 V (RMS), 400 V (V _p), derates at 20 dB/decade to 5 V (RMS) above 250 kHz ±5 div
Input sensitivity Maximum input voltage Position range	input sensitivity $\leq 5 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ at 50Ω at $1 M\Omega$ at 50Ω at $1 M\Omega$ input sensitivity $\leq 112 \text{ mV/div}$	±2.5 % DC, AC, GND 0.5 mV/div to 1 V/div 0.5 mV/div to 10 V/div 5 V (RMS), max. 30 V (V _p) 300 V (RMS), 400 V (V _p), derates at 20 dB/decade to 5 V (RMS) above 250 kHz ±5 div ±(30 V – 5 div × input sensitivity)
Input sensitivity Maximum input voltage Position range	input sensitivity $\leq 5 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ at 50Ω at $1 \text{ M}\Omega$ at 50Ω at $1 \text{ M}\Omega$ input sensitivity $\geq 112 \text{ mV/div} \text{ to } 1 \text{ V/div}$ $\geq 33.8 \text{ mV/div} \text{ to } 111 \text{ mV/div}$ $0.5 \text{ mV/div} \text{ to } 33.6 \text{ mV/div}$	±2.5 % DC, AC, GND 0.5 mV/div to 1 V/div 0.5 mV/div to 10 V/div 5 V (RMS), max. 30 V (V _p) 300 V (RMS), 400 V (V _p), derates at 20 dB/decade to 5 V (RMS) above 250 kHz ±5 div ±(30 V - 5 div × input sensitivity) ±(10 V - 5 div × input sensitivity)
Input sensitivity Maximum input voltage Position range Offset range at 50 Ω	input sensitivity $\leq 5 \text{ mV/div to } \geq 1 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ at 50 Ω at 1 MΩ at 50 Ω at 1 MΩ input sensitivity $\geq 112 \text{ mV/div to } 1 \text{ V/div}$ $\geq 33.8 \text{ mV/div to } 111 \text{ mV/div}$ 0.5 mV/div to 33.6 mV/div input sensitivity	±2.5 % DC, AC, GND 0.5 mV/div to 1 V/div 0.5 mV/div to 10 V/div 5 V (RMS), max. 30 V (V _p) 300 V (RMS), 400 V (V _p), derates at 20 dB/decade to 5 V (RMS) above 250 kHz ±5 div ±(30 V - 5 div × input sensitivity) ±(10 V - 5 div × input sensitivity) ±(2 V - 5 div × input sensitivity)
Input sensitivity Maximum input voltage Position range Offset range at 50 Ω	input sensitivity $\leq 5 \text{ mV/div to} \geq 1 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ at 50Ω at $1 \text{ M}\Omega$ at 50Ω at $1 \text{ M}\Omega$ at 50Ω at $1 \text{ M}\Omega$ input sensitivity $\geq 112 \text{ mV/div to } 1 \text{ V/div}$ $\geq 33.8 \text{ mV/div to } 111 \text{ mV/div}$ $0.5 \text{ mV/div to } 33.6 \text{ mV/div}$ input sensitivity $\geq 515 \text{ mV/div to } 10 \text{ V/div}$	±2.5 % DC, AC, GND 0.5 mV/div to 1 V/div 0.5 mV/div to 10 V/div 5 V (RMS), max. 30 V (V _p) 300 V (RMS), 400 V (V _p), derates at 20 dB/decade to 5 V (RMS) above 250 kHz ±5 div ±(30 V - 5 div × input sensitivity) ±(10 V - 5 div × input sensitivity) ±(2 V - 5 div × input sensitivity)
Input sensitivity Maximum input voltage Position range Offset range at 50 Ω	input sensitivity $\leq 5 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ at 50Ω at $1 \text{ M}\Omega$ at 50Ω at $1 \text{ M}\Omega$ at 50Ω at $1 \text{ M}\Omega$ input sensitivity $\geq 112 \text{ mV/div}$ to 1 V/div $\geq 33.8 \text{ mV/div}$ to 111 mV/div 0.5 mV/div to 33.6 mV/div input sensitivity $\geq 515 \text{ mV/div}$ to 10 V/div $\geq 50.5 \text{ mV/div}$ to 510 mV/div	±2.5 % DC, AC, GND 0.5 mV/div to 1 V/div 0.5 mV/div to 10 V/div 5 V (RMS), max. 30 V (V _p) 300 V (RMS), 400 V (V _p), derates at 20 dB/decade to 5 V (RMS) above 250 kHz ±5 div ±(30 V – 5 div × input sensitivity) ±(10 V – 5 div × input sensitivity) ±(2 V – 5 div × input sensitivity) ±(250 V – 5 div × input sensitivity)
Input sensitivity Maximum input voltage Position range Offset range at 50 Ω Offset range at 1 MΩ	input sensitivity $\leq 5 \text{ mV/div to} \geq 1 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ at 50Ω at $1 \text{ M}\Omega$ at 50Ω at $1 \text{ M}\Omega$ at 50Ω at $1 \text{ M}\Omega$ input sensitivity $\geq 112 \text{ mV/div to } 1 \text{ V/div}$ $\geq 33.8 \text{ mV/div to } 111 \text{ mV/div}$ $0.5 \text{ mV/div to } 33.6 \text{ mV/div}$ input sensitivity $\geq 515 \text{ mV/div to } 10 \text{ V/div}$	±2.5 % DC, AC, GND 0.5 mV/div to 1 V/div 0.5 mV/div to 10 V/div 5 V (RMS), max. 30 V (V _p) 300 V (RMS), 400 V (V _p), derates at 20 dB/decade to 5 V (RMS) above 250 kHz ±5 div ±(30 V - 5 div × input sensitivity) ±(10 V - 5 div × input sensitivity) ±(2 V - 5 div × input sensitivity) ±(25 V - 5 div × input sensitivity) ±(25 V - 5 div × input sensitivity) ±(25 V - 5 div × input sensitivity)
Input sensitivity Maximum input voltage Position range Offset range at 50 Ω	input sensitivity $\leq 5 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ at 50Ω at $1 \text{ M}\Omega$ at 50Ω at $1 \text{ M}\Omega$ at 50Ω at $1 \text{ M}\Omega$ input sensitivity $\geq 112 \text{ mV/div}$ to 1 V/div $\geq 33.8 \text{ mV/div}$ to 111 mV/div 0.5 mV/div to 33.6 mV/div input sensitivity $\geq 515 \text{ mV/div}$ to 10 V/div $\geq 50.5 \text{ mV/div}$ to 510 mV/div	±2.5 % DC, AC, GND 0.5 mV/div to 1 V/div 0.5 mV/div to 10 V/div 5 V (RMS), max. 30 V (V _p) 300 V (RMS), 400 V (V _p), derates at 20 dB/decade to 5 V (RMS) above 250 kHz ±5 div ±(30 V - 5 div × input sensitivity) ±(10 V - 5 div × input sensitivity) ±(2 V - 5 div × input sensitivity) ±(25 V - 5 div × input sensitivity) ±(25 V - 5 div × input sensitivity) ±(25 V - 5 div × input sensitivity) ±(20 V - 5 div × input sensitivity)
Input sensitivity Maximum input voltage Position range Offset range at 50 Ω Offset range at 1 MΩ	input sensitivity $\leq 5 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ at 50Ω at $1 \text{ M}\Omega$ at 50Ω at $1 \text{ M}\Omega$ input sensitivity $\geq 112 \text{ mV/div}$ to 1 V/div $\geq 33.8 \text{ mV/div}$ to 111 mV/div 0.5 mV/div to 33.6 mV/div input sensitivity $\geq 515 \text{ mV/div}$ to 10 V/div $\geq 50.5 \text{ mV/div}$ to 510 mV/div 0.5 mV/div to 50 mV/div	±2.5 % DC, AC, GND 0.5 mV/div to 1 V/div 0.5 mV/div to 10 V/div 5 V (RMS), max. 30 V (V _p) 300 V (RMS), 400 V (V _p), derates at 20 dB/decade to 5 V (RMS) above 250 kHz ±5 div ±(30 V - 5 div × input sensitivity) ±(10 V - 5 div × input sensitivity) ±(2 V - 5 div × input sensitivity) ±(25 V - 5 div × input sensitivity) ±(25 V - 5 div × input sensitivity) ±(25 V - 5 div × input sensitivity) ±(0.5 % × offset + 0.1 div × input sensitivity + 0.5 mV)
Input sensitivity Maximum input voltage Position range Offset range at 50 Ω Offset range at 1 MΩ	input sensitivity $\leq 5 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ at 50Ω at $1 \text{ M}\Omega$ at 50Ω at $1 \text{ M}\Omega$ input sensitivity $\geq 112 \text{ mV/div}$ to 1 V/div $\geq 33.8 \text{ mV/div}$ to 111 mV/div 0.5 mV/div to 33.6 mV/div input sensitivity $\geq 515 \text{ mV/div}$ to 10 V/div $\geq 50.5 \text{ mV/div}$ to 510 mV/div 0.5 mV/div to 50 mV/div after adequate suppression of	±2.5 % DC, AC, GND 0.5 mV/div to 1 V/div 0.5 mV/div to 10 V/div 5 V (RMS), max. 30 V (V _p) 300 V (RMS), 400 V (V _p), derates at 20 dB/decade to 5 V (RMS) above 250 kHz ±5 div ±(30 V - 5 div × input sensitivity) ±(10 V - 5 div × input sensitivity) ±(2 V - 5 div × input sensitivity) ±(25 V - 5 div × input sensitivity) ±(25 V - 5 div × input sensitivity) ±(0.5 % × offset + 0.1 div × input sensitivity + 0.5 mV) ±(DC gain accuracy × reading - net
Input sensitivity Maximum input voltage Position range Offset range at 50 Ω Offset range at 1 MΩ	input sensitivity $\leq 5 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ at 50Ω at $1 \text{ M}\Omega$ at 50Ω at $1 \text{ M}\Omega$ input sensitivity $\geq 112 \text{ mV/div}$ to 1 V/div $\geq 33.8 \text{ mV/div}$ to 111 mV/div 0.5 mV/div to 33.6 mV/div input sensitivity $\geq 515 \text{ mV/div}$ to 10 V/div $\geq 50.5 \text{ mV/div}$ to 510 mV/div 0.5 mV/div to 50 mV/div after adequate suppression of measurement noise by using either high-	±2.5 % DC, AC, GND 0.5 mV/div to 1 V/div 0.5 mV/div to 10 V/div 5 V (RMS), max. 30 V (V _p) 300 V (RMS), 400 V (V _p), derates at 20 dB/decade to 5 V (RMS) above 250 kHz ±5 div ±(30 V - 5 div × input sensitivity) ±(10 V - 5 div × input sensitivity) ±(2 V - 5 div × input sensitivity) ±(25 V - 5 div × input sensitivity) ±(25 V - 5 div × input sensitivity) ±(25 V - 5 div × input sensitivity) ±(0.5 % × offset + 0.1 div × input sensitivity + 0.5 mV)
Input sensitivity Maximum input voltage Position range Offset range at 50 Ω Offset range at 1 MΩ	input sensitivity $\leq 5 \text{ mV/div to} \geq 1 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ at 50 Ω at 1 MΩ at 50 Ω at 1 MΩ at 50 Ω at 1 MΩ input sensitivity $\geq 112 \text{ mV/div}$ $\geq 112 \text{ mV/div to} \leq 112 \text{ mV/div}$ $\geq 33.8 \text{ mV/div to} \leq 111 \text{ mV/div}$ 0.5 mV/div to 33.6 mV/div input sensitivity $\geq 515 \text{ mV/div to} \leq 50.5 \text{ mV/div to} \leq 50.5 \text{ mV/div}$ 0.5 mV/div to 510 mV/div 0.5 mV/div to 50 mV/div	±2.5 % DC, AC, GND 0.5 mV/div to 1 V/div 0.5 mV/div to 10 V/div 5 V (RMS), max. 30 V (V _p) 300 V (RMS), 400 V (V _p), derates at 20 dB/decade to 5 V (RMS) above 250 kHz ±5 div ±(30 V - 5 div × input sensitivity) ±(10 V - 5 div × input sensitivity) ±(2 V - 5 div × input sensitivity) ±(25 V - 5 div × input sensitivity) ±(25 V - 5 div × input sensitivity) ±(0.5 % × offset + 0.1 div × input sensitivity + 0.5 mV) ±(DC gain accuracy × reading - net
Input sensitivity Maximum input voltage Position range Offset range at 50 Ω Offset range at 1 MΩ	input sensitivity $\leq 5 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ at 50Ω at $1 \text{ M}\Omega$ at 50Ω at $1 \text{ M}\Omega$ input sensitivity $\geq 112 \text{ mV/div}$ to 1 V/div $\geq 33.8 \text{ mV/div}$ to 111 mV/div 0.5 mV/div to 33.6 mV/div input sensitivity $\geq 515 \text{ mV/div}$ to 10 V/div $\geq 50.5 \text{ mV/div}$ to 510 mV/div 0.5 mV/div to 50 mV/div after adequate suppression of measurement noise by using either high-	±2.5 % DC, AC, GND 0.5 mV/div to 1 V/div 0.5 mV/div to 10 V/div 5 V (RMS), max. 30 V (V _p) 300 V (RMS), 400 V (V _p), derates at 20 dB/decade to 5 V (RMS) above 250 kHz ±5 div ±(30 V - 5 div × input sensitivity) ±(10 V - 5 div × input sensitivity) ±(2 V - 5 div × input sensitivity) ±(25 V - 5 div × input sensitivity) ±(25 V - 5 div × input sensitivity) ±(0.5 % × offset + 0.1 div × input sensitivity + 0.5 mV) ±(DC gain accuracy × reading - net

RMS noise floor at 1 MΩ (meas.)	Input sensitivity	R&S®			
, ,	,	RTA4004	RTA4004 with	RTA4004 with	RTA4004 with
			-B243 option	-B245 option	-B2410 option
	10 V/div	226 mV	250 mV	298 mV	298 mV
	5 V/div	124 mV	132 mV	182 mV	182 mV
	2 V/div	53.1 mV	58.7 mV	81.5 mV	81.5 mV
	1 V/div	29.1 mV	32.9 mV	45.6 mV	45.6 mV
	500 mV/div	12.4 mV	13.2 mV	18.2 mV	18.2 mV
	200 mV/div	5.3 mV	5.9 mV	8.2 mV	8.2 mV
	100 mV/div	3.0 mV	3.4 mV	4.7 mV	4.7 mV
	50 mV/div	1.2 mV	1.2 mV	1.6 mV	1.6 mV
	20 mV/div	0.54 mV	0.59 mV	0.83 mV	0.83 mV
	10 mV/div	0.28 mV	0.32 mV	0.44 mV	0.44 mV
	5 mV/div	0.16 mV	0.19 mV	0.25 mV	0.25 mV
	2 mV/div	0.11 mV	0.14 mV	0.19 mV	0.19 mV
	1 mV/div	0.09 mV	0.10 mV	0.13 mV	0.13 mV
	0.5 mV/div	0.09 mV	0.10 mV	0.13 mV	0.13 mV
RMS noise floor at 50 Ω (meas.)	Input sensitivity	R&S®			
		RTA4004	RTA4004 with	RTA4004 with	RTA4004 with
			-B243 option	-B245 option	-B2410 option
	1 V/div	22.7 mV	22.8 mV	25.1 mV	31.4 mV
	500 mV/div	12.6 mV	13.7 mV	15.4 mV	19.8 mV
	200 mV/div	5.5 mV	6.2 mV	7.0 mV	9.1 mV
	100 mV/div	2.7 mV	3.0 mV	3.4 mV	4.6 mV
	50 mV/div	1.4 mV	1.6 mV	1.8 mV	2.4 mV
	20 mV/div	0.53 mV	0.58 mV	0.65 mV	0.86 mV
	10 mV/div	0.26 mV	0.28 mV	0.32 mV	0.41 mV
	5 mV/div	0.15 mV	0.18 mV	0.20 mV	0.27 mV
	2 mV/div	0.07 mV	0.09 mV	0.10 mV	0.13 mV
	1 mV/div	0.06 mV	0.07 mV	0.08 mV	0.11 mV
	0.5 mV/div	0.05 mV	0.07 mV	0.08 mV	0.11 mV

Horizontal system

Timebase range		selectable between
		0.5 ns/div and 500 s/div
Channel deskew		±500 ns
Trigger offset range	minimum	memory depth
		actual sampling rate
	maximum	2 ³³
		actual sampling rate
Modes		normal, roll
Channel-to-channel skew		< 200 ps (meas.)
Timebase accuracy	after delivery/calibration, at +23 °C	±0.5 ppm
	during calibration interval	±1 ppm

Acquisition system

Maximum realtime sampling rate	normal mode	2.5 Gsample/s
	interleaved mode,	5 Gsample/s
	if following channels are not used	
	simultaneously:	
	 channel 1 and channel 2 	
	 channel 3 and channel 4 	
	logic channels	
Memory depth per channel	normal mode	100 Msample per channel
	interleaved mode,	200 Msample per channel
	if following channels are not used	
	simultaneously:	
	 channel 1 and channel 2 	
	 channel 3 and channel 4 	
	logic channels	
Acquisition modes	sample	first sample in decimation interval
	peak detect	largest and smallest sample in decimation interval
	high resolution	average value of all samples in decimation interval
	envelope	envelope of acquired waveforms
	average	average over a series of acquired waveforms
	envelope + peak detect	envelope of acquired waveforms with active peak detect
	envelope + high resolution	envelope of acquired waveforms with active high resolution
	average + high resolution	average over a series of acquired high
		resolution waveforms
Number of averaged waveforms		2 to 100 000
Waveform acquisition rate	dot display, single channel, auto record length	up to 64 000 waveforms/s

Trigger system

Trigger level	range	±5 div from center of screen
Trigger modes		auto, normal, single, n single
Hold-off range	time	inactive or 51.2 ns to 13.7 s
Trigger types		edge, width, video, pattern, runt, rise time, fall time, serial bus, line, timeout
Edge trigger A	trigger events	rising edge, falling edge, both edges
	R&S®RTA4004	channel 1, channel 2, channel 3, channel 4, logic channels from D15 to D0 (with R&S®RTA-B1 option), external trigger input
	trigger coupling	DC, AC (attenuates < 10 Hz (meas.)), LF reject (attenuates < 10 kHz (meas.))
	trigger filter	HF reject (attenuates > 100 kHz (meas.)), noise reject (attenuates > 100 MHz (meas.))
	selectable trigger hysteresis	automatic, small, medium, large

Trigger A sensitivity hysteresis mode	with DC, AC, LF reject, noise reject	
automatic	1 GHz, 500 MHz, 350 MHz	$2.2 mV_{nn}$
		$> \frac{2.2 mV_{pp}}{input sensitivity} + 1 div (nom.)$ (input sensitivity: [mV/div])
		, , , , , , , , , , , , , , , , , , , ,
	200 MHz, 100 MHz	$> \frac{1.5 mV_{pp}}{input sensitivity} + 0.8 div (nom.)$
		$> \frac{PP}{input \ sensitivity} + 0.8 \ div \ (nom.)$
		(input sensitivity: [mV/div])
	20 MHz	$0.6mV_{pp}$
		$> \frac{0.6 mV_{pp}}{input sensitivity} + 0.4 div (nom.)$
		(input sensitivity: [mV/div])
	with HF reject	
	all input sensitivities	1 div (meas.)
Edge trigger A and B	trigger events	rising edge, falling edge, both edges
	sources for A trigger	
	R&S®RTA4004	channel 1, channel 2, channel 3,
		channel 4, logic channels from D15 to D0
	trigger coupling of A trigger	(with R&S®RTA-B1 option)
	sources for B trigger	DC
	R&S®RTA4004	channel 1, channel 2, channel 3,
	NGO KIMAOOA	channel 4, logic channels from D15 to D0
		(with R&S®RTA-B1 option)
	trigger coupling of B trigger	DC
	selectable trigger hysteresis for A and B	small, medium, large
	trigger	
	trigger B mode	after time or after events
	trigger B minimum time	3.2 ns
	trigger B maximum time	100 s
Width trigger	trigger B events trigger events	1 to 65535 pulse width is smaller, greater, equal,
widin ingger	trigger events	unequal, inside interval, outside interval
	minimum pulse width	3.2 ns
	maximum pulse width	6.8 s
	polarity	positive, negative
	sources	
	R&S®RTA4004	channel 1, channel 2, channel 3,
		channel 4, logic channels from D15 to D0
	a ala atabla triaggar by atarasia	(with R&S®RTA-B1 option)
Timeout trigger	selectable trigger hysteresis trigger events	small, medium, large greater than timeout
rimeout tilgger	minimum timeout	3.2 ns
	maximum timeout	6.8 s
	polarity	stays high, stays low, stays high or low
	sources	, , , , , , , , , , , , , , , , , , ,
	R&S®RTA4004	channel 1, channel 2, channel 3,
		channel 4, logic channels from D15 to D0
		(with R&S®RTA-B1 option)
\	selectable trigger hysteresis	small, medium, large
Video trigger	trigger events	selectable line, all lines, even frame,
	supported standards	odd frame, all frames PAL, NTSC, SECAM, PAL-M, SDTV 576i,
	supported standards	HDTV 720p, HDTV 1080i, HDTV 1080p
	sources	1.5.1 1200, 1151 1 10001, 1151 1 10000
	R&S®RTA4004	channel 1, channel 2, channel 3,
		channel 4, ext. trigger input
	sync pulse polarity	positive, negative
		- · · · · · · · · · · · · · · · · · · ·

Pattern trigger	trigger events	logic condition between active channels			
	sources				
	R&S®RTA4004	channel 1, channel 2, channel 3, channel 4, logic channels from D15 to D0 (with R&S®RTA-B1 option)			
	state of channels	high, low, don't care			
	logic between channels	and/or			
	condition	true, false			
	duration condition	smaller, greater, equal, unequal, inside interval, outside interval, timeout			
	minimum duration time	3.2 ns			
	maximum duration time	6.8 s			
Runt trigger		triggers on pulse of positive, negative or either polarity that crosses one threshold but fails to cross a second threshold before crossing the first one again			
Rise time, fall time	trigger events	time between the crossing of two selectable levels is smaller, greater, equal, unequal, inside interval, outside interval			
	minimum rise time	3.2 ns			
	maximum rise time	6.8 s			
	polarity	rising edge, falling edge, both edges			
	sources				
	R&S®RTA4004	channel 1, channel 2, channel 3, channel 4			
Serial bus trigger	supported standards	- ' '			
	R&S®RTA-K1 option	I ² C, SSPI (two-wire, MOSI/MISO), SPI (three-wire, MOSI/MISO)			
	R&S®RTA-K2 option	UART/RS-232/RS-422/RS-485 (RX/TX)			
	R&S®RTA-K3 option	CAN/LIN			
	R&S®RTA-K5 option	audio (I ² S, LJ, RJ, TDM)			
	R&S®RTA-K6 option	MIL-STD-1553			
	R&S®RTA-K7 option	ARINC 429			
External trigger input	input impedance	$1 M\Omega \pm 1 \%$ with 14 pF ± 2 pF (meas.)			
	maximum input voltage at 1 $M\Omega$	300 V (RMS), 400 V (V_p), derates at 20 dB/decade to 5 V (RMS) above 250 kHz			
	trigger level	±5 V			
	sensitivity	> 300 mV (V _{pp})			
	coupling	DC, AC, LF reject			
Trigger output	functionality	A pulse is generated for every acquisition trigger event.			
	output voltage				
	at high impedance	0 V to 4.8 V			
	at 50 Ω	0 V to 2.4 V			
	pulse polarity	high active			

Waveform measurements

Automatic measurements	measurements on channels, math waveforms, reference waveforms	burst width, count positive pulses, count negative pulses, count falling edges, count rising edges, mean value, RMS cycle, RMS, mean cycle, peak peak, peak+, peak-, frequency, period, amplitude, top level, base level, positive overshoot, negative overshoot, pulse width+, pulse width-, duty cycle+, duty cycle-, rise time, fall time, delay, phase, crest factor, slew rate+, slew rate-, σ.std. deviation, σ.std. deviation cycle	
	reference levels	lower, middle and upper level in percentage	
	statistics	maximum, minimum, mean, standard deviation and measurement count for each automatic measurement	
	number of active measurements	8	
Cursor measurements	type	vertical, horizontal, vertical and horizonta V-marker	
	functions	x and y tracking, coupling of cursors, set to trace, set to screen	
Quick measurements	function	fast overview of measurements from one channel, some measurements displayed with result lines in diagram	
	sources		
	R&S®RTA4004	channel 1, channel 2, channel 3, channel 4	
	measurements displayed in diagram	mean, max. peak, min. peak, rise time, fall time	
	numerically displayed measurements	RMS cycle, peak-to-peak voltage, period, frequency	

Digital voltmeter

Accuracy		related to channel settings of voltmeter
		source
Measurements		DC, AC+DC RMS, AC RMS
Sources	R&S®RTA4004	channel 1, channel 2, channel 3,
		channel 4
Number of measurements		up to 4
Resolution		up to 3 digits
Bandwidth		1 MHz

Counter

Measurements		frequency, period
Sources	R&S®RTA4004	channel 1, channel 2, channel 3,
		channel 4, trigger signal source
Number of measurements		2
Resolution		7 digits
Frequency range		0.05 Hz to bandwidth of oscilloscope
		(limited by bandwidth of trigger filter)

Mask testing

Sources	R&S®RTA4004	channel 1, channel 2, channel 3, channel 4
Mask definition		acquired waveform with user-defined tolerance, can be stored and restored
Result statistics		completed acquisitions, passed and failed acquisitions (absolute and in percent), test duration
Actions on mask violation		sound, acquisition stop, screenshot, save waveform, pulse out (AUX OUT connector)
Captured segments		all segments, failed segments

Waveform maths

Number of math equations		up to 5
Functions		addition, subtraction, multiplication,
		division, square, square root, absolute
		value, reciprocal, inverse, log10, ln,
		derivation, integration, low pass, high pass
	R&S®RTA4004	channel 1, channel 2, channel 3,
		channel 4, math waveforms 1 to 4

Fast Fourier transformation (FFT)

Sources	R&S®RTA4004	channel 1, channel 2, channel 3, channel 4, math waveforms, references	
Setup parameters		start frequency, stop frequency, center	
		frequency, frequency span, vertical scale,	
		vertical position, resolution bandwidth,	
		gate (time range and position)	
Windows		Hanning, Hamming, Blackman,	
		rectangular, flat top	
Waveform arithmetic		none, min. hold, max. hold, average	
		(selectable 2 to 1024)	
Scaling		dBm, dBV, dBμV, V (RMS)	

Search function

Functions	search types	edge, width, peak, rise/fall time, runt,
		data2clock, pattern, window, protocol
		(available with R&S®RTA-K3,
		R&S®RTA-K6 and R&S®RTA-K7 options)
	configuration	manual level setting on screen, level with
		selectable hysteresis
	display of search events	up to 10 000 events in diagram and in
		result table
	markers on search events	up to 32 markers
	navigation in search events (stop mode)	knob (if result table is active)
Sources	R&S®RTA4004	channel 1, channel 2, channel 3,
		channel 4, math waveforms from 1 to 5,
		D15 to D0 (with R&S®RTA-B1 option)

Display characteristics

Diagram types	manually changeable vertical window size	Yt, XY, zoom, FFT, spectrogram (with R&S®RTA-K18 option)
XY mode		parallel display of XY diagram and Yt diagrams of input signals for X, Y
Zoom		horizontal and vertical zoom, split screen with overview signal and zoomed signal
Interpolation		sin(x)/x, linear, sample & hold
FFT mode		split screen with Yt diagrams and
		dedicated frequency diagram,
		spectrogram (with R&S®RTA-K18 option)
Waveform display		lines, dots only
Persistence		50 ms to 12.8 s; infinite
Special display mode		inverse brightness, waveform color modes
		for analog channels (temperature, fire,
		rainbow)
Diagram grid		lines, reticle, none, with annotation, track
		grid
Reference signals		up to 4 reference signals

Protocol and logic

Bus decode	number of bus signals	4 ¹
	bus types	parallel, parallel clocked
	R&S®RTA-K1 option	SSPI, SPI, I ² C
	R&S®RTA-K2 option	UART/RS-232/RS-422/RS-485
	R&S®RTA-K3 option	CAN, LIN
	R&S®RTA-K5 option	I ² S, LJ, RJ, TDM
	R&S®RTA-K6 option	MIL-STD-1553
	R&S®RTA-K7 option	ARINC 429
	display types	decoded bus, logical signal,
		frame table (depends on decoded bus)
	position and size	size and position on screen selectable
	data format of decoded bus	hex, decimal, binary, octal, ASCII

History and segmented memory

Acquisition memory		automatic, predef	ined, manual	
	automatic	automatic segme	nt size and numbers	3
	predefined	defined size and automatic numbers		
	manual	user-defined size and numbers		
Memory segmentation	function	memory segments for the acquisition		
	number of segments 2	record length	segments	total memory
			(up to)	(per channel)
		5 ksample	87 380	436.9 Msample
		10 ksample	87 380	873.8 Msample
		20 ksample	43 690	873.8 Msample
		50 ksample	17 476	873.8 Msample
		100 ksample	9 708	970.8 Msample
		200 ksample	5 140	1028 Msample
		500 ksample	2 131	1065.5 Msample
		1 Msample	1 065	1065 Msample
		2 Msample	536	1072 Msample
		5 Msample	214	1070 Msample
		10 Msample	107	1070 Msample
		20 Msample	53	1060 Msample
		50 Msample	21	1050 Msample
		100 Msample	10	1000 Msample
		200 Msample	5	1000 Msample
	Segmentation is active spectrum analysis.	on all analog and lo	ogic channels, proto	col decoding and

 $^{^{\}rm 1}$ If a bidirectional bus is used (e.g. UART RX/TX or SPI MOSI/MISO), two bus decoders are occupied.

² At interleaved mode.

Fast-segmented mode		continuous recording of waveforms in acquisition memory without interruption due to visualization; blind time between consecutive acquisitions less than 200 ns (up to 2 000 000 waveforms/s)	
History mode	function	The history mode always provides access to past acquisitions in the segmented memory.	
	timestamp resolution	3.2 ns	
	history player	replays the recorded waveforms; repetition possible; adjustable speed; manual next/previous segment; numerical segment number input	
	analyze options	overlay all segments, average all segments, envelope all segments	

Miscellaneous

Save/recall	device settings	save and recall on internal file system or
Gavo/100aii	device county	USB memory stick or on a PC via web
		interface or USB-MTP
	reference waveforms	save and recall on internal file system or
		USB memory stick or on a PC via web
		interface or USB-MTP
	waveforms	save on USB memory stick or download and save on a PC via web interface or
		USB-MTP, available file formats: BIN, CSV, TXT float
		(MSB/LSB first)
	screenshots	save on USB memory stick or download and save on a PC via web interface or USB-MTP,
		available file formats: BMP, PNG
	device settings	save and recall on internal file system or USB memory stick or on a PC via web interface or USB-MTP
Camera key		configurable camera key, actions on
		press:
		save screenshot
		one-touch
	save screenshot	one-touch off
	one-touch	one or more from the list:
		setup
		 screenshots (PNG, color)
		waveforms (BIN-MSB, CI, display data)
		• references
		 search event table
		 bus table
		 statistics
Instrument security		secure erasure of internal file system and
,		all settings
Menu languages		available menu languages:
3 3		English
		German
		French
		Spanish
		Italian
		 Portuguese
		Czech
		Polish
		Russian
		Simplified Chinese
		Traditional Chinese
		Korean
		Japanese
Help		online help, available languages: • English
Undo/Redo		deep Undo/Redo function
22711040		doop ondo/1000 fullotion

Input and outputs

Front		
Channel inputs		BNC, for details see Vertical system
	probe interface	auto detection of passive probes,
		Rohde & Schwarz active probe interface
External trigger input		BNC, for details see Trigger system
	probe interface	auto detection of passive probes
Waveform generator		BNC, for details see R&S®RTA-B6,
(requires R&S®RTA-B6 option)		waveform generator,
		demo lug and GND lug
Probe compensation output	signal shape	rectangle
	frequency	1 kHz
	voltage	$V_{low} = 0 \text{ V}, V_{high} = 1.5 \text{ V to } 3.3 \text{ V (meas.)}$
Pattern source	P3 to P0	4 lugs, for details see R&S®RTA-B6,
(requires R&S®RTA-B6 option)		4-bit pattern generator
	frequency	1 mHz to 25 MHz
	voltage	$V_{low} = 0 \text{ V}, V_{high} = 1.5 \text{ V to } 3.3 \text{ V (meas.)}$
Ground lug		connected to ground
USB host interface		1 port, type A plug, version 2.0,
		flash drives only
Rear		
Ethernet interface		1 port, 1 Gbit
AUX OUT (BNC)	trigger out,	for details see Trigger system
	reference frequency	10 MHz ±3.5 ppm (meas.)
	mask violation	pulse
USB device interface		1 port, type B plug, version 2.0
Fixation loop		for securing the instrument with a cable
Security slot		for standard Kensington style lock
Right side		
Digital channel inputs	D15 to D8, D7 to D0	requires R&S®RTA-B1 option

General data

Display		
Туре		10.1" WXGA display with capacitive touch
Resolution		1280 x 800 pixel (WXGA)
Temperature		
Temperature loading	operating temperature range	0 °C to +50 °C
	storage temperature range	-40 °C to +70 °C
Climatic loading	·	+25 °C/+40 °C at 85 % rel. humidity cyclic,
C		in line with IEC 60068-2-30
Altitude		
Operating		up to 3000 m above sea level
Nonoperating		up to 4600 m above sea level
Mechanical resistance		ap to 1000 iii abovo oca iovo.
Vibration	sinusoidal	5 Hz to 150 Hz, max. 1.8 g at 55 Hz;
Vibration	omadordar	0.5 g from 55 Hz to 150 Hz,
		in line with EN 60068-2-6
		MIL-PRF-28800F, 4.5.5.3.2 sinusoidal
		vibration, class 3 and 4
	random	10 Hz to 300 Hz.
	random	
		acceleration 1.2 g (RMS),
		in line with EN 60068-2-64,
		MIL-PRF-28800F, 4.5.5.3.1 random
<u> </u>		vibration, class 3 and 4
Shock		40 g shock spectrum,
		in line with MIL-STD-810E,
		method no. 516.4, procedure I,
		MIL-PRF-28800F, 4.5.5.4.1 functional
		shock, 30 g, 11 ms, halfsine
EMC		
RF emission		in line with CISPR 11/EN 55011 group 1
		class A (for a shielded test setup);
		the instrument complies with the emission
		requirements stipulated by EN 55011,
		EN 61326-1 and EN 61326-2-1 class A,
		making the instrument suitable for use in
		industrial environments
Immunity		in line with IEC/EN 61326-1 table 2,
		immunity test requirements for industrial
Certifications		immunity test requirements for industrial environments ³
Certifications Calibration interval		immunity test requirements for industrial environments ³ VDE, _C CSA _{US} , KC
Calibration interval		immunity test requirements for industrial environments ³
Calibration interval Power supply		immunity test requirements for industrial environments ³ VDE, _C CSA _{US} , KC 1 year
Calibration interval		immunity test requirements for industrial environments ³ VDE, _C CSA _{US} , KC 1 year 100 V to 240 V at 50 Hz to 60 Hz,
Calibration interval Power supply AC supply		immunity test requirements for industrial environments ³ VDE, cCSA _{US} , KC 1 year 100 V to 240 V at 50 Hz to 60 Hz, 1.6 A to 0.7 A
Calibration interval Power supply AC supply Power consumption		immunity test requirements for industrial environments ³ VDE, _c CSA _{US} , KC 1 year 100 V to 240 V at 50 Hz to 60 Hz, 1.6 A to 0.7 A max. 160 W
Calibration interval Power supply AC supply		immunity test requirements for industrial environments ³ VDE, cCSA _{US} , KC 1 year 100 V to 240 V at 50 Hz to 60 Hz, 1.6 A to 0.7 A max. 160 W in line with
Calibration interval Power supply AC supply Power consumption		immunity test requirements for industrial environments ³ VDE, cCSA _{US} , KC 1 year 100 V to 240 V at 50 Hz to 60 Hz, 1.6 A to 0.7 A max. 160 W in line with IEC 61010-1, IEC 61010-2-030
Calibration interval Power supply AC supply Power consumption		immunity test requirements for industrial environments ³ VDE, cCSA _{US} , KC 1 year 100 V to 240 V at 50 Hz to 60 Hz, 1.6 A to 0.7 A max. 160 W in line with IEC 61010-1, IEC 61010-2-030 EN 61010-1, EN 61010-2-030
Calibration interval Power supply AC supply Power consumption		immunity test requirements for industrial environments ³ VDE, cCSA _{US} , KC 1 year 100 V to 240 V at 50 Hz to 60 Hz, 1.6 A to 0.7 A max. 160 W in line with IEC 61010-1, IEC 61010-2-030 EN 61010-1, EN 61010-2-030 CAN/CSA-C22.2 No. 61010-1
Calibration interval Power supply AC supply Power consumption		immunity test requirements for industrial environments ³ VDE, cCSA _{US} , KC 1 year 100 V to 240 V at 50 Hz to 60 Hz, 1.6 A to 0.7 A max. 160 W in line with IEC 61010-1, IEC 61010-2-030 EN 61010-1, EN 61010-2-030 CAN/CSA-C22.2 No. 61010-1 CAN/CSA-C22.2 No. 61010-2-030
Calibration interval Power supply AC supply Power consumption		immunity test requirements for industrial environments ³ VDE, cCSA _{US} , KC 1 year 100 V to 240 V at 50 Hz to 60 Hz, 1.6 A to 0.7 A max. 160 W in line with IEC 61010-1, IEC 61010-2-030 EN 61010-1, EN 61010-2-030 CAN/CSA-C22.2 No. 61010-1
Calibration interval Power supply AC supply Power consumption		immunity test requirements for industrial environments ³ VDE, cCSA _{US} , KC 1 year 100 V to 240 V at 50 Hz to 60 Hz, 1.6 A to 0.7 A max. 160 W in line with IEC 61010-1, IEC 61010-2-030 EN 61010-1, EN 61010-2-030 CAN/CSA-C22.2 No. 61010-1 CAN/CSA-C22.2 No. 61010-2-030 UL 61010-1, UL 61010-2-030
Calibration interval Power supply AC supply Power consumption Safety	W×H×D	immunity test requirements for industrial environments ³ VDE, cCSA _{US} , KC 1 year 100 V to 240 V at 50 Hz to 60 Hz, 1.6 A to 0.7 A max. 160 W in line with IEC 61010-1, IEC 61010-2-030 EN 61010-1, EN 61010-2-030 CAN/CSA-C22.2 No. 61010-1 CAN/CSA-C22.2 No. 61010-2-030
Calibration interval Power supply AC supply Power consumption Safety Mechanical data	W×H×D	immunity test requirements for industrial environments ³ VDE, cCSA _{US} , KC 1 year 100 V to 240 V at 50 Hz to 60 Hz, 1.6 A to 0.7 A max. 160 W in line with IEC 61010-1, IEC 61010-2-030 EN 61010-1, EN 61010-2-030 CAN/CSA-C22.2 No. 61010-1 CAN/CSA-C22.2 No. 61010-2-030 UL 61010-1, UL 61010-2-030
Calibration interval Power supply AC supply Power consumption Safety Mechanical data		immunity test requirements for industrial environments ³ VDE, cCSA _{US} , KC 1 year 100 V to 240 V at 50 Hz to 60 Hz, 1.6 A to 0.7 A max. 160 W in line with IEC 61010-1, IEC 61010-2-030 EN 61010-1, EN 61010-2-030 CAN/CSA-C22.2 No. 61010-1 CAN/CSA-C22.2 No. 61010-2-030 UL 61010-1, UL 61010-2-030 390 mm × 220 mm × 152 mm (15.35 in × 8.66 in × 5.98 in)
Calibration interval Power supply AC supply Power consumption Safety Mechanical data Dimensions	W x H x D without options (nom.) maximum sound pressure level at a	immunity test requirements for industrial environments ³ VDE, cCSA _{US} , KC 1 year 100 V to 240 V at 50 Hz to 60 Hz, 1.6 A to 0.7 A max. 160 W in line with IEC 61010-1, IEC 61010-2-030 EN 61010-1, EN 61010-2-030 CAN/CSA-C22.2 No. 61010-1 CAN/CSA-C22.2 No. 61010-2-030 UL 61010-1, UL 61010-2-030

 $^{^3}$ Test criterion is displayed noise level within ± 1 div for input sensitivity of 5 mV/div.

Options

R&S®RTA-B1

Mixed signal option, additional 16 log	jic channels	
Vertical system		16 logic channels (from D15 to D0)
Input channels		16 logic channels (from D15 to D0)
Arrangement of input channels		arranged in two logic probes with 8 channels each, assignment of the logic
		probes to the channels D15 to D8 and D7
		to D0
Innut impedance		$100 \text{ k}\Omega \pm 2 \% \parallel \sim 4 \text{ pF (meas.)}$ at probe
Input impedance		tips
Maximum input frequency	signal with minimum input voltage swing	400 MHz (meas.)
	and hysteresis setting: normal	, ,
Maximum input voltage		±40 V (V _p)
Minimum input voltage swing		500 mV (V _{pp}) (meas.)
Threshold groups		from D15 to D12, D11 to D8, D7 to D4 and
		D3 to D0
Threshold level	user range	±8 V in 25 mV steps
	predefined	CMOS 2.5 V, TTL 1.4 V, ECL -1.3 V
Threshold accuracy		±(100 mV + 3 % of threshold setting)
Comparator hysteresis		small, medium, large
Horizontal system		
Channel deskew	range for each channel	±500 ns
Channel-to-channel skew		< 200 ps (meas.) for same vertical settings
		on the channels
Acquisition system		
Sampling rate	two logic probes	2.5 Gsample/s on each channel
	one logic probe	5 Gsample/s on each channel
Memory depth	two logic probes	100 Msample for every channel
	one logic probe	200 Msample for every channel
Trigger system		see chapter Trigger system of the base
NA/		unit
Waveform measurements		all about the DAT to DO
Measurement sources		all channels from D15 to D0
Automatic measurements		positive pulse width, negative pulse width,
		period, frequency, burst width, delay,
		phase, positive duty cycle, negative duty
		cycle, positive pulse count, negative pulse
		count, rising edge count, falling edge
		count
Additional cursor function		display of hex. value at the cursor position
Display characteristics		
Channel activity display		independent of the oscilloscope
		acquisition, the state (stays low, stays high
		or toggles) of the channels from D15 to D0
		is displayed

R&S®RTA-B6

Waveform generator and 4-bit patter	rn generator	
Waveform generator		
Resolution		14 bit
Sample rate		250 Msample/s
Output impedance		50 Ω ±1 % (meas.)
Amplitude	level	
	in to high Z	20 mV to 10 V (V _{pp})
	in to 50 Ω	10 mV to 5 V (V _{pp})
	accuracy	1.5 %
DC offset	level	
	in to high Z	± 5 V
	in to 50 Ω	± 2.5 V
	accuracy	1.5 % or ±3 mV whatever is greater
Sine	frequency	0.1 Hz to 25 MHz
	SFDR	> 40 dBc (meas.)
	THD	> 40 dBc (meas.)
Rectangle	frequency	0.1 Hz to 10 MHz
Pulse	frequency	0.1 Hz to 10 MHz
uisc	edge time	adjustable
	duty cycle	1 % to 99 %
Ramp, triangle, sinc, exponential	frequency	0.1 Hz to 1 MHz
	' '	
Arbitrary	sample rate	max. 10 Msample/s
	memory depth	32k point
Noise	bandwidth	max. 25 MHz
	level	0 to 100 % of signal amplitude
Modulation	AM	
	function	sine, rectangle, triangle, ramp
	frequency	0.1 Hz to 1 MHz
	depth	0 to 100 %
	FM	
	function	sine, rectangle, triangle, ramp
	frequency	0.1 Hz to 1 MHz
	deviation	depends on modulation frequency
	ASK	, ,
	function	sine, rectangle, triangle, ramp
	frequency	0.1 Hz to 1 MHz
	ASK depth	0 to 100 %
	FSK	0.100.70
	function	sine, rectangle, triangle, ramp
	frequency	0.1 Hz to 1 MHz
	FSK rate	
0		0.1 Hz to carrier frequency/2
Sweep	start frequency	1 Hz to 25 MHz
	stop frequency	1 Hz to 25 MHz
	sweep time	1 ms to 10 s
	sweep type	linear, logarithmic, triangle
Burst	number of cycle	1 to 1024
	idle time	28 ns to 17 s
	start phase	0° to 360°
	trigger	continuous, manually
4-bit pattern generator		
Functions		probe adjust/square wave, bus signal
		source 4-bit counter, programmable 4-bi
		pattern
Bus signal source		SPI, I ² C, UART, CAN, LIN
Ŭ	bandwidth	9600 bit/s to 1 Mbit/s
4-bit counter	frequency	25 mHz to 50 MHz
Programmable pattern	sample rate	20 ns to 1 s, up/down
rogrammable pattern	square wave frequency	1 mHz to 500 kHz
	square wave nequency	I IIII IZ IO OOU KAZ
		9006 bit per channel
	memory depth pattern idle time	8096 bit per channel 50 ns to 1 s

I ² C triggering and decoding				
Bus configuration	sources for SCL and SDA	sources for SCL and SDA		
	R&S®RTA4004	channel 1, channel 2, channel 3,		
		channel 4, logic channels from D15 to D0		
		(with R&S®RTA-B1 option)		
	bit rate	up to 10 Mbps		
	size of address	7 bit or 10 bit		
	size of data	8 bit		
	label list	associate frame identifier with symbolic ID		
Trigger	trigger events	start, stop, restart, missing acknowledge, address (7 bit or 10 bit), data, address and data		
	offset for trigger on data	0 data byte to 4095 data byte		
	data pattern width	up to 3 sequential data byte		
Decode	displayed signals	bus signal, logic signal or both		
	color coding of bus signal	address, data, start, stop, ACK, NACK,		
		error		
	displayed format of address	hex, symbolic ID (label list)		
	displayed format of data	ASCII, binary, decimal or hex		
SPI triggering and decoding		•		
Bus configuration	sources for CS, CLK, MOSI and MISC	0		
	R&S®RTA4004	channel 1, channel 2, channel 3,		
		channel 4, logic channels from D15 to D0 (with R&S®RTA-B1 option)		
	bit rate	up to 25 Mbps		
	chip select (CS)	active low, active high or missing (SSPI)		
	clock (CLK) slope	rise or fall		
	data symbol size	1 bit to 32 bit		
	idle time for SSPI	12.8 ns to 26.8 ms		
Trigger	trigger events	start of frame, end of frame, bit number,		
		data pattern		
	selectable bit number	0 to 4095		
	offset for trigger on data pattern	0 to 4095 bit		
	data pattern size	1 bit to 32 bit		
Decode	displayed signals	bus signal, logic signal or both		
	color coding of bus signal	data, start, stop, error		
	displayed format of data	ASCII, binary, decimal or hex		
	data decoding	MSB or LSB first		

Bus configuration	source for RX and TX	source for RX and TX		
	R&S®RTA4004	channel 1, channel 2, channel 3, channel 4, logic channels from D15 to D0 (with R&S®RTA-B1 option)		
	bit rate	300 bps to 1 Mbps or user-selectable up to 6 Mbps		
	end of frame	timeout		
	signal polarity	idle low, idle high		
	data symbol size	5 bit to 9 bit		
	parity	none, even or odd		
	stop bits	1, 1.5 or 2		
	Idle time	up to 26.8 ms		
Trigger	trigger events	start bit, start of frame, symbol number, any symbol, pattern of symbols, parity error, stop bit error, break		
	offset for trigger on data symbol	0 to 4095 symbols		
	data symbol pattern width	1 to floor (32/symbol size) symbols		
Decode	displayed signals	bus signal, logic signal or both		
	color coding of bus signal	data, start, stop, error, parity		
	displayed format of data	ASCII, binary, decimal or hex		

CAN triggering and decoding		
Bus configuration	signal type	CAN_H, CAN_L
	bit rate	10/20/33.3/50/83.3/100/125/250/500/
		1000 kbps or user-selectable in range
		from 100 bps to 2 Mbps
	sampling point	10 % to 90 % within bit period
	label list	associate frame identifier with symbolic ID
Trigger	trigger events	start of frame, frame type, identifier,
33	331 1 1	identifier + data, error condition (any
		combination of CRC error, bit stuffing
		error, form error and ACK error)
	identifier setup	frame type (data, remote or both),
	identifier setup	identifier type (11 bit or 29 bit);
		condition =, ≠, >, <; identifier selectable
		from label list
	data actus	
	data setup	data pattern up to 8 byte (hex or binary); condition =, \neq , >, <
Decode	displayed signals	bus signal, logic signal or both
	color coding of bus signal	start of frame, identifier, DLC, data
	3 24 2 2 3 24	payload, CRC, ACK, end of frame, error
		frame, overload frame, CRC error, bit
		stuffing error, ACK error
	displayed format of data	hex, decimal, binary, ASCII
	frame table	decode results displayed as tabulated list,
	Tamo table	errors highlighted in red; frame navigation
		data export as CSV file
Search	search events	frame, error, identifier, identifier + data,
Search	Search events	identifier + error
	frame event setup	start of frame, end of frame, overload
	frame event setup	
		frame, error frame, data ID 11 bit, data ID
		29 bit, remote ID 11 bit, remote ID 29 bit
	error event setup	any combination of CRC error, bit stuffing
		error, form error and ACK error
	identifier setup	frame type (data, remote or both),
		identifier type (11 bit or 29 bit);
		condition =, ≠, >, <; identifier selectable
		from label list
	data setup	data pattern up to 8 byte (hex or binary);
		condition =, ≠, >, <
	event table	search results displayed as tabulated list;
		event navigation
LIN triggering and decoding Bus configuration	version	1.3, 2.x or SAE J602; mixed traffic is
Das comiguration	VOISION	supported
	bit rate	1.2/2.4/4.8/9.6/10.417/19.2 kbps or user-
	Dit late	selectable in range from 100 bps to
		5 Mbps
	polority	·
	polarity	active high or active low
Telegrania	label list	associate frame identifier with symbolic ID
Trigger	Source	1 14 1 15 15
	R&S®RTA4004	channel 1, channel 2, channel 3,
		channel 4, logic channels from D15 to D0
		(with R&S®RTA-B1 option)
	trigger events	start of frame (sync break), identifier,
		identifier + data, wakeup frame, error
		condition (any combination of checksum
		error, parity error and sync field error)
	identifier setup	range from 0d to 63d; condition =, ≠, >, <;
		identifier selectable from label list
	data setup	data pattern up to 8 byte (hex or binary);
	·	condition =, ≠, >, <

Decode	displayed signals	bus signal, logic signal or both
	color coding of bus signal	frame, frame identifier, parity, data
		payload, checksum, error condition
	displayed format of data	hex, decimal, binary, ASCII
	frame table	decode results displayed as tabulated list, errors highlighted in red; frame navigation;
Canada	a a such assenta	data export as CSV file
Search	search events	frame, error, identifier, identifier + data, identifier + error
	frame event setup	start of frame, wake up
	error event setup	any combination of checksum error, parity error and sync field error
	identifier setup	range from 0d to 63d; condition =, \neq, >, <; identifier selectable from label list
	data setup	data pattern up to 8 byte (hex or binary); condition =, \neq , >, <
	event table	search results displayed as tabulated list; event navigation

Bus configuration	source (data, clock, word/sync)	ing and decoding source (data, clock, word/sync)		
	R&S®RTA4004	channel 1, channel 2, channel 3, channel 4, logic channels from D15 to D0 (with R&S®RTA-B1 option)		
	thresholds	per-channel threshold (analog channels), per-group threshold (logic channels), assisted threshold configuration (find level		
	bit rate	up to 30 Mbps		
	signal type	I ² S standard, left justified, right justified, TDM		
	polarity	data: active high, active low; clock: rising edge, falling edge; word/sync: normal, inverted		
	word length	2 bit to 32 bit		
	bit order	most significant bit first (MSBF), least significant bit first (LSBF)		
	I ² S-specific setup	,		
	first channel	left, right		
	LJ/RJ-specific setup	1		
	first channel	left, right		
	channel offset	0 to 31 bit		
	TDM-specific setup			
	number of channels	1 to 8		
	channel length	2 bit to 32 bit		
	channel offset	0 to (channel length – word length) bits		
	channel delay	0 to 31 bit		
Trigger	trigger events	data, window, word/sync, error condition		
111990	data setup	define individual value and condition for each audio channel; condition =, ≠, >, <, inside range, outside range, don't care; trigger when "all" or "any" audio channel conditions are met in single audio frame		
	window setup	audio channel setup same as data setup; user-defined window length up to 4 000 000 000 frames		
	word/sync setup	rising edge, falling edge		
Decode	displayed signals	bus signal, stacked bus signal, logic signa		
	color coding of bus signal	color-coded audio channels		
	displayed format of data	hex, signed decimal, binary, ASCII		
	frame table	decode results displayed as tabulated list with timestamp; frame navigation; data export as CSV file		
	track of audio waveform	displays audio channel content as a waveform that is time-correlated to the source signals; user can activate, scale and position each audio channel individually		

MIL-STD-1553 triggering and de		
Protocol configuration	source	
	R&S [®] RTA4004	channel 1, channel 2, channel 3, channel 4, logic channels from D15 to D0 (with R&S®RTA-B1 option)
	bit rate	standard bit rate (1 Mbit/s)
	polarity	normal, inverted
	label list	associate frame identifier with symbolic ID
	auto threshold setup	assisted threshold configuration
	timing	max response (4 µs to 200 µs)
Triagor		sync, word, command word, status word,
Trigger	trigger event setup	command and data word, error condition
	sync setup	all words, command/status word, data word
	word setup	all words, command word, status word, data word
	command word setup (type: address/word)	RT address (condition =, \neq , \geq , \leq , in range, out of range); direction (T/R); subaddress
		(condition =, \neq , \geq , \leq , in range, out of range); data word count (condition =, \neq , \geq ,
	command word setup (type: mode code)	≤, in range, out of range) RT address (condition =, ≠, ≥, ≤, in range,
	,	out of range); subaddress (0, 31 or either); mode code from labeled dropdown list
	status word setup	RT address; status flags (message error, instrumentation, service request,
		broadcast command, busy, subsystem
		flag, dynamic bus control, terminal flag) individually configurable (1, 0, don't care)
	command and data word setup	transmission type (BC-RT, RT-BC, BC-BC, mode code); RT address (condition =,
		\neq , \geq , \leq , in range, out of range); subaddress (condition =, \neq , \geq , \leq , in range, out of
		range); data word count (condition =, ≠, ≥, ≤, in range, out of range); data pattern up
		to 4 words long (condition =, \neq , \geq , \leq , in
		range, out of range); payload data index (condition =)
	error condition setup	any combination of sync error, Mancheste error, parity error, timing error (see
		protocol configuration)
Decode	display signals	bus signal; symbolic ID in bus signal when label list in use
	color coding	sync, RT address, subaddress, mode code, status bit field, data, error condition
	displayed format of data	hex, decimal, binary, ASCII
	frame table	decode results displayed as tabulated list,
		errors highlighted in red; frame navigation; data export as CSV file; column with
		symbolic ID when label list in use
Search	search events	word, command word, mode code, status word, command and data word, error
	word setup	command, status, data
	command word setup	see trigger settings for "command word setup (type: address/word)"
	mode code setup	see trigger settings for "command word setup (type: mode code)"
	status word setup	see trigger settings for "status word setup"
	command and data word setup	see trigger settings for "command and
	error condition setup	data word setup" all, sync, parity, manchester, timing

Protocol configuration	ding source		
	R&S®RTA4004	channel 1, channel 2, channel 3, channel 4, logic channels from D15 to D0 (with R&S®RTA-B1 option)	
	bit rate	high (100 kbit/s), low (12.5 kbit/s), or user-defined in range 10 kbit/s to 1 Mbit/s	
	polarity	A leg, B leg, normal, inverted	
	label list	associate numeric label with symbolic ID; optional definition of ARINC word format in terms of availability of label-specific SDI and SSM fields	
	auto threshold setup	assisted threshold configuration	
Trigger	trigger event setup	word, label, label and data, error condition transmission interval	
	word setup	word start, word stop	
	label setup	label (condition =, \neq , \geq , \leq , in range, out of range)	
	data setup	data pattern up to 23 bit long (condition =, ≠, ≥, ≤, in range, out of range); data bit offset; SDI (00,01,10,11); SSM (00,01,10,11); label list can be used to determine availability of trigger properties SSM and SDI for given label value	
	error condition setup	any combination of coding error, parity error, gap error	
	transmission interval setup	label (condition =); SDI (optional); time interval (condition >, <, in range, out of range)	
Decode	display signals	bus signal, logic signal or both; symbolic ID in bus signal when label list in use	
	color coding	word begin, word end, label, SDI, data, SSM, parity, error	
	displayed format of data	hex, decimal, binary, ASCII	
	frame table	decode results displayed as tabulated list, errors highlighted in red; frame navigation data export as CSV file; column with symbolic ID when label list in use	
Search	search events	word, label, label and data, error condition	
	word setup	word start, word stop	
	label setup	see trigger settings for "label setup"	
	data setup	see trigger settings for "data setup"	
	error condition setup	coding error, parity error, gap error, any	

Spectrum analysis and spectrogra	am		
General	additional displays	spectrum traces and/or spectrogram	
Spectrum	sources		
	R&S®RTA4004	channel 1, channel 2, channel 3, channel 4	
	setup parameters	center frequency, frequency span, automatic RBW, resolution bandwidth, gate position, gate width, vertical scale, vertical position, spectrum mode	
	scaling	dBm, dBV, dBμV, V (RMS)	
	span	1 kHz to 1.25 GHz	
	resolution bandwidth	span/10 ≥ RBW ≥ span/1000	
	windows	flat top, Hanning, Hamming, Blackman, rectangular	
	trace types	normal, max. hold, min. hold, average	
	spectrum mode	optimized for dynamic range of frequency domain (disables time domain for the same channel)	
Spectrogram	color	rainbow, temp. color, monochrome	
Marker		standard search	
Marker	peak marker search		
		parameter: min. level advanced search	
		parameter: min. level, excursion,	
		maximum width, distance to next peak	
	reference marker	selection via index or frequency range	
	markers on peak	up to 100 markers	
	sources	any spectrum trace	
	table	frequency and magnitude, absolute or	
	100.0	relative to reference marker	
	marker result display	indicated at wave form: level, frequency	
Cursor	measurements on spectrum traces	level, frequency, level and frequency, V-marker	
	additional actions for cursor	coupling of cursors, set to trace, set to screen, track scaling, set next and previous peak	
Spectrogram measurements	two time cursor	t1, t2, delta t, total time, relative time between segments	

Power analysis General description	neral description The R&S®RTA-K31 power analysis option extends the R&S®R measurement functionality focused on switched mode power s		
Input	DC/DC converters. quality	evaluation of power quality at an AC input; measures real power, apparent power, reactive power, power factor and phase angle of power, frequency, crest factor, RMS of voltage and current	
	harmonics	measures up to the 334th harmonic of the incoming line frequency; precompliance checking for IEC 61000-3-2 (A, B, C, D), RTCA DO-160, MIL-STD-1399, max. limit checks	
	inrush current	measures peak inrush current and electrical charge within up to 3 configurable measurement zones to analyze the inrush and post-inrush behavior	
	consumption	long term measurement of consumed power and energy to analyze nonperiodical signals of e.g. standby devices	
Switching/control loop	slew rate	The minimum and maximum slew rate of current or voltage is measured at start and end of the switching cycle.	
	modulation	measures modulation of switching frequency, duty cycle (±) and pulse width	
	dynamic on-resistance	measures resistance of the switching transistor(s) in active state	
Power path	efficiency	measures input and output power to calculate the efficiency of a power device	
	switching loss	measures switching loss and conduction loss of a power device	
	safe operating area (SOA)	checks violation of voltage and current limits in which a power device can operat without damage; current versus voltage view (linear or log); violation mask is use defined and editable in linear and log-log views; save/load of masks; export of mas violation data	
	turn on/off time	measures relationship between AC and DC current, when turning SMPS off and on	
Output	ripple	measures AC components of output voltage or current, AC RMS, mean, period, frequency, duty cycles, min./max./peak-to-peak amplitude	
	spectrum	FFT analysis of output, measurement of frequency peaks	
	transient response	This measurement captures the device behavior between the event of load changes and stabilization; includes peak (voltage, time), settling time, rise time, overshoot and delay	
Deskew	automated	By using the R&S®RT-ZF20 probe deskew and calibration test fixture and Rohde & Schwarz voltage and current probes, the skew between the signals is compensated automatically.	
Zero offset	automated	automatic compensation of input offset	
Reporting	Report data can be saved for every measurement. Report generation using user- selected test results from historical and current tests. Put repeated and/or different measurements in one report. R&S®Oscilloscope Report Creator can be downloaded from Rohde & Schwarz website free-of-charge.		

Frequency response analysis -	Bode plot	
Stimulus	frequency mode	single sweep or repeated sweep
	frequency range	10 Hz to 25 MHz
	amplitude mode	fixed or amplitude profile
	amplitude level	20 mV to 10 V into high Z
		10 mV to 5 V into 50 Ω
Input and output sources	R&S [®] RTA4004	channel 1, channel 2, channel 3,
		channel 4
Number of test points		10 points to 500 points per decade
Dynamic range		typ. > 70 dB based on 0 dBm
		(630 mV (V_{pp}) into 50 Ω,
		gain noise < 1 dB, phase noise < 5°)
Measurement		dual pair of tracking gain and phase
		cursors
Diagram types	manually changeable vertical window size	parallel display of result window and input
		and output signal view
Result table		navigation and export functions
Scaling	during and after test	auto-scale and manual scaling and
		positioning

Ordering information

Designation	Туре	Order No.
Choose your R&S®RTA4000 base model		
Oscilloscope, 200 MHz, 4 channels	R&S®RTA4004	1335.7700.04
Base unit (including standard accessories: 500 MHz passive probe pe	r channel, power cord)	
Choose your bandwidth upgrade		
Upgrade of R&S®RTA4004 oscilloscopes to 350 MHz bandwidth	R&S®RTA-B243	1335.7846.02
Upgrade of R&S®RTA4004 oscilloscopes to 500 MHz bandwidth	R&S®RTA-B245	1335.7852.02
Upgrade of R&S®RTA4004 oscilloscopes to 1 GHz bandwidth	R&S®RTA-B2410	1335.7869.02
Choose your options		
Mixed signal upgrade for non-MSO models, 400 MHz	R&S®RTA-B1	1335.7823.02
Arbitrary waveform and 4-bit pattern generator	R&S®RTA-B6	1335.7830.02
I ² C/SPI serial triggering and decoding	R&S®RTA-K1	1335.7681.02
UART/RS-232/RS-422/RS-485 serial triggering and decoding	R&S®RTA-K2	1335.7698.02
CAN/LIN serial triggering and decoding	R&S®RTA-K3	1335.7717.02
Audio (I ² S, LJ, RJ, TDM) triggering and decoding	R&S®RTA-K5	1335.7723.02
MIL-STD-1553 serial triggering and decoding	R&S®RTA-K6	1335.7730.02
ARINC 429 serial triggering and decoding	R&S®RTA-K7	1335.7746.02
Spectrum analysis and spectrogram ⁴	R&S®RTA-K18	1335.7752.02
Power analysis	R&S®RTA-K31	1335.7769.02
Frequency response analysis (Bode plot)	R&S®RTA-K36	1335.7975.02
Application bundle ⁵ , consists of the following options:	R&S®RTA-PK1	1335.7775.02
R&S®RTA-K1, R&S®RTA-K2, R&S®RTA-K3, R&S®RTA-K5,		
R&S®RTA-K6, R&S®RTA-K7, R&S®RTA-K18, R&S®RTA-K31,		
R&S®RTA-K36, R&S®RTA-B6		
Application bundle ⁶ , consists of the following options:	R&S®RTA-PK1US	1335.7998.02
R&S®RTA-K1, R&S®RTA-K2, R&S®RTA-K3, R&S®RTA-K5,		
R&S®RTA-K6, R&S®RTA-K7, R&S®RTA-K31, R&S®RTA-K36,		
R&S®RTA-B6		
Choose your additional probes		1
Single-ended passive probes		
500 MHz, 10 MΩ, 10:1, 300 V, 10 pF, 5 mm	R&S®RT-ZP05S	1333.2401.02
500 MHz, 10 MΩ, 10:1, 400 V, 9.5 pF, 2.5 mm	R&S®RT-ZP10	1409.7550.00
38 MHz, 1 MΩ, 1:1, 55 V, 39 pF, 2.5 mm	R&S®RT-ZP1X	1333.1370.02
Active broadband probes: single-ended		1 1 2 2 2 1 2 1 2 1 2 1 2 1 2 1 2 1 2 1
1.0 GHz, 10:1, 1 MΩ, BNC interface	R&S®RT-ZS10L	1333.0815.02
1.0 GHz, active, 1 MΩ, Rohde & Schwarz probe interface	R&S®RT-ZS10E	1418.7007.02
1.0 GHz, active, 1 MΩ, R&S®ProbeMeter, micro button,	R&S®RT-ZS10	1410.4080.02
Rohde & Schwarz probe interface	11.00 11.1 20.10	
1.5 GHz, active, 1 MΩ, R&S®ProbeMeter, micro button,	R&S®RT-ZS20	1410.3502.02
Rohde & Schwarz probe interface		
Active broadband probes: differential		
1.0 GHz, active, differential, 1 MΩ, R&S®ProbeMeter, micro button,	R&S®RT-ZD10	1410.4715.02
incl. 10:1 external attenuator, 1 M Ω , 70 V DC, 46 V AC (peak),		1 2 2 2 2 2 2
Rohde & Schwarz probe interface		
1.5 GHz, active, differential, 1 MΩ, R&S®ProbeMeter, micro button,	R&S®RT-ZD20	1410.4409.02
Rohde & Schwarz probe interface		
Power rail probe	1	1
2.0 GHz, 1:1, 50 kΩ, ±0.85 V, ±60 V offset, Rohde & Schwarz probe	R&S®RT-ZPR20	1800.5006.02
interface		. 333.3330.02
High voltage single-ended passive probes		
250 MHz, 100:1, 100 MΩ, 850 V, 6.5 pF	R&S®RT-ZH03	1333.0873.02
400 MHz, 100:1, 50 MΩ, 1000 V, 7.5 pF	R&S®RT-ZH10	1409.7720.02
400 MHz, 1000:1, 50 MΩ, 1000 V, 7.5 pF	R&S®RT-ZH11	1409.7737.02

⁻

⁴ The R&S[®]RTA-K18 option is not distributed in North America.

 $^{^{\}rm 5}~$ The R&S $^{\rm 8}$ RTA-PK1 option is not distributed in North America.

⁶ The R&S®RTA-PK1US option is only distributed in North America.

Designation	Туре	Order No.
High voltage probes: differential		'
25 MHz, 20:1/200:1, 4 MΩ, 1.4 kV (CAT III), BNC interface	R&S®RT-ZD002	1337.9700.02
25 MHz, 10:1/100:14 MΩ, 700 V (CAT II), BNC interface	R&S®RT-ZD003	1337.9800.02
100 MHz, 8 MΩ, 1 kV (RMS) (CAT III), BNC interface	R&S®RT-ZD01	1422.0703.02
200 MHz, 10:1, ±20 V, BNC interface	R&S®RT-ZD02	1333.0821.02
800 MHz, 10:1, 200 kΩ, ±15 V, BNC interface	R&S®RT-ZD08	1333.0838.02
200 MHz, 250:1/25:1, 5 MΩ, 750 V (peak), 300 V CAT III,	R&S®RT-ZHD07	1800.2307.02
Rohde & Schwarz probe interface		
100 MHz, 500:1/50:1, 10 MΩ, 1500 V (peak), 1000 V CAT III,	R&S®RT-ZHD15	1800.2107.02
Rohde & Schwarz probe interface		
200 MHz, 500:1/50:1, 10 MΩ, 1500 V (peak), 1000 V CAT III,	R&S®RT-ZHD16	1800.2207.02
Rohde & Schwarz probe interface		
100 MHz, 1000:1/100:1, 40 MΩ, 6000 V (peak), 1000 V CAT III,	R&S®RT-ZHD60	1800.2007.02
Rohde & Schwarz probe interface		
Current probes		
20 kHz, AC/DC, 0.01 V/A and 0.001 V/A, ±200 A and ±2000 A,	R&S®RT-ZC02	1333.0850.02
BNC interface		
100 kHz, AC/DC, 0.1 V/A, 30 A, BNC interface	R&S®RT-ZC03	1333.0844.02
2 MHz, AC/DC, 0.01 V/A, 500 A (RMS), Rohde & Schwarz probe	R&S®RT-ZC05B	1409.8204.02
interface		
10 MHz, AC/DC, 0.01 V/A, 150 A (RMS), BNC interface	R&S®RT-ZC10	1409.7750K02
10 MHz, AC/DC, 0.01 V/A, 150 A (RMS), Rohde & Schwarz probe	R&S®RT-ZC10B	1409.8210.02
interface		
50 MHz, AC/DC, 0.1 V/A, 30 A (RMS), Rohde & Schwarz probe	R&S®RT-ZC15B	1409.8227.02
interface		
100 MHz, AC/DC, 0.1 V/A, 30 A (RMS), BNC interface	R&S®RT-ZC20	1409.7766K02
100 MHz, AC/DC, 0.1 V/A, 30 A (RMS), Rohde & Schwarz probe	R&S®RT-ZC20B	1409.8233.02
interface		
120 MHz, AC/DC, 1 V/A, 5 A (RMS), BNC interface	R&S®RT-ZC30	1409.7772K02
EMC near-field probes		
Probe set for E and H near-field measurements, 30 MHz to 3 GHz	R&S®HZ-15	1147.2736.02
Logic probes		
400 MHz logic probe, 8 channels	R&S®RT-ZL04	1333.0721.02
Probe accessories		
Probe power supply for R&S®RT-ZC10/20/30	R&S®RT-ZA13	1409.7789.02
External attenuator 10:1, 2.0 GHz, 1.3 pF, 60 V DC,	R&S®RT-ZA15	1410.4744.02
42.4 V AC (peak) for R&S®RT-ZD20/30 probes		
Probe pouch	R&S®RT-ZA19	
Power deskew and calibration test fixture	R&S®RT-ZF20	1800.0004.02
3D positioner with central tensioning knob for easy clamping and	R&S®RT-ZA1P	1326.3641.02
positioning of probes (span width: 200 mm, clamping range: 15 mm)		
Choose your accessories	D. 00DTD T/	1000 (500 00
Front cover	R&S®RTB-Z1	1333.1728.02
Soft bag	R&S®RTB-Z3	1333.1734.02
Transit case	R&S®RTB-Z4	1335.9290.02
Rackmount kit	R&S®ZZA-RTB2K	1333.1728.02

Warranty		
Base unit		3 years
All other items ⁷		1 year
Options		
Extended warranty, one year	R&S®WE1	Please contact your local
Extended warranty, two years	R&S®WE2	Rohde & Schwarz sales
Extended warranty with calibration coverage, one year	R&S®CW1	office.
Extended warranty with calibration coverage, two years	R&S®CW2	
Extended warranty with accredited calibration coverage,	R&S®AW1	
one year		
Extended warranty with accredited calibration coverage,	R&S®AW2	
two years		

Extended warranty with a term of one and two years (WE1 and WE2)

Repairs carried out during the contract term are free of charge 8. Necessary calibration and adjustments carried out during repairs are also covered.

Extended warranty with calibration (CW1 and CW2)

Enhance your extended warranty by adding calibration coverage at a package price. This package ensures that your Rohde & Schwarz product is regularly calibrated, inspected and maintained during the term of the contract. It includes all repairs ⁸ and calibration at the recommended intervals as well as any calibration carried out during repairs or option upgrades.

Extended warranty with accredited calibration (AW1 and AW2)

Enhance your extended warranty by adding accredited calibration coverage at a package price. This package ensures that your Rohde & Schwarz product is regularly calibrated under accreditation, inspected and maintained during the term of the contract. It includes all repairs ⁸ and accredited calibration at the recommended intervals as well as any accredited calibration carried out during repairs or option upgrades.

⁷ For options that are installed, the remaining base unit warranty applies if longer than 1 year. Exception: all batteries have a 1 year warranty.

⁸ Excluding defects caused by incorrect operation or handling and force majeure. Wear-and-tear parts are not included.